



PARADIM
AN NSF MATERIALS INNOVATION PLATFORM

Lecture #2—

Nuts and Bolts of Oxide MBE: Growth Conditions, Sources, and Crucibles

Darrell G. Schlom

Nuts and Bolts of Oxide MBE

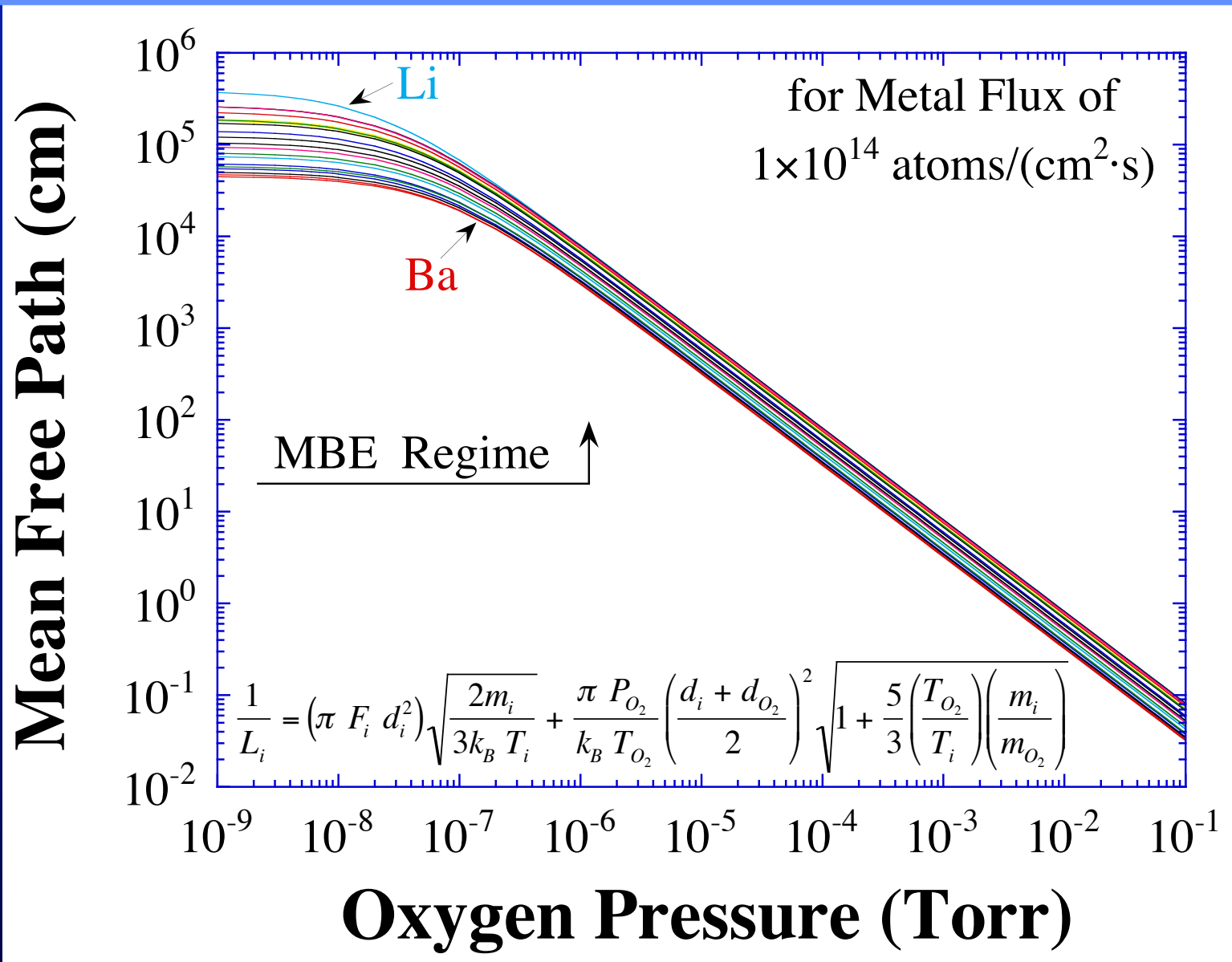
How to grow your favorite oxide by MBE?

- Lecture #2—*Growth Conditions, Sources, and Crucibles*
- Lecture #3—*Composition Control and Calibration*
- Lecture #4—*Epitaxy, Substrates, and Crystal Growth*

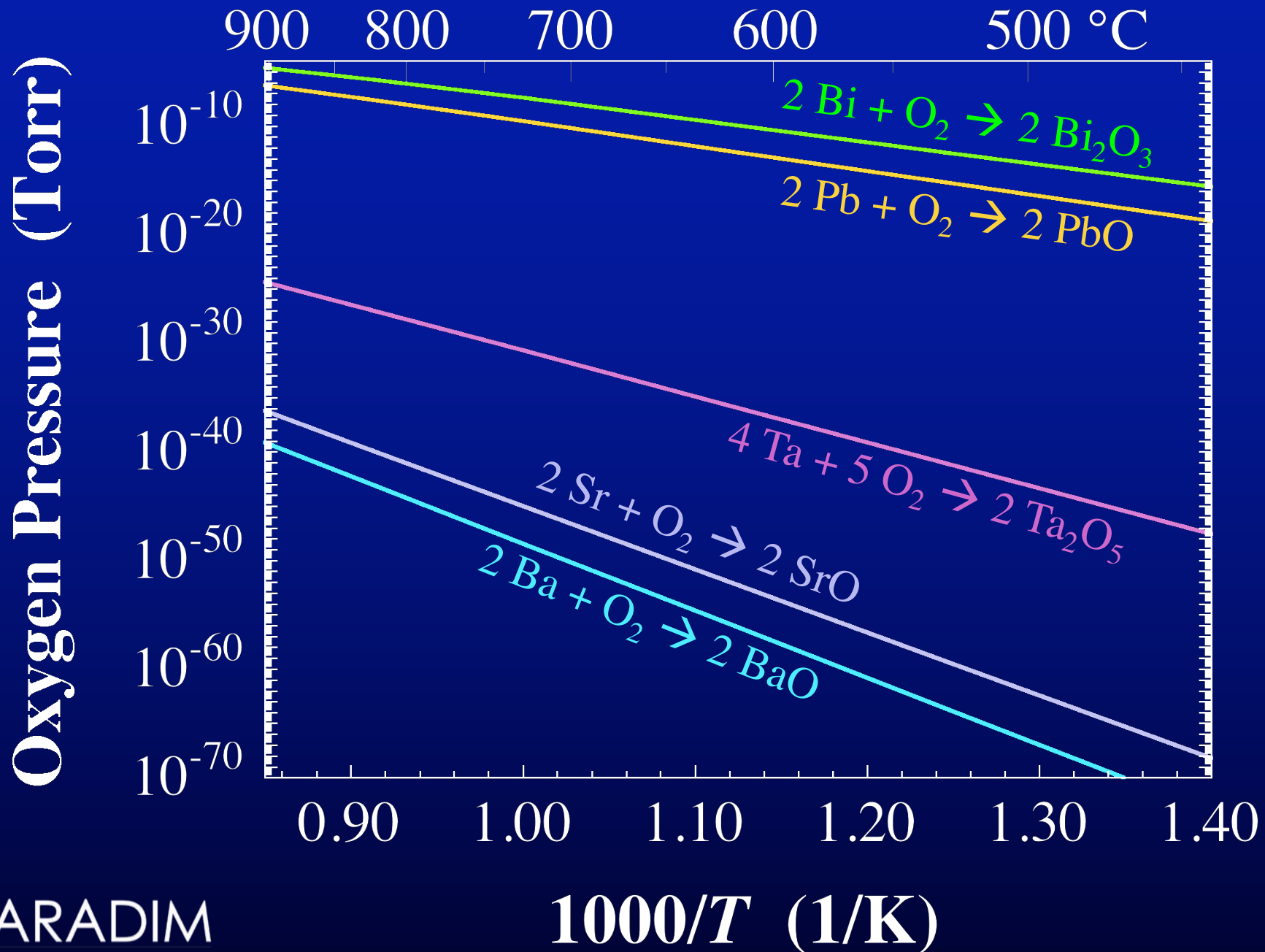
Nuts and Bolts of Oxide MBE

- Mean Free Path (maximum P_{O_2})
- Minimum P_{O_2} , need for P_{O_3}
- Optimal T_{sub}
- MBE System
- MBE Sources
- Crucibles

Maximum O₂ Pressure for MBE

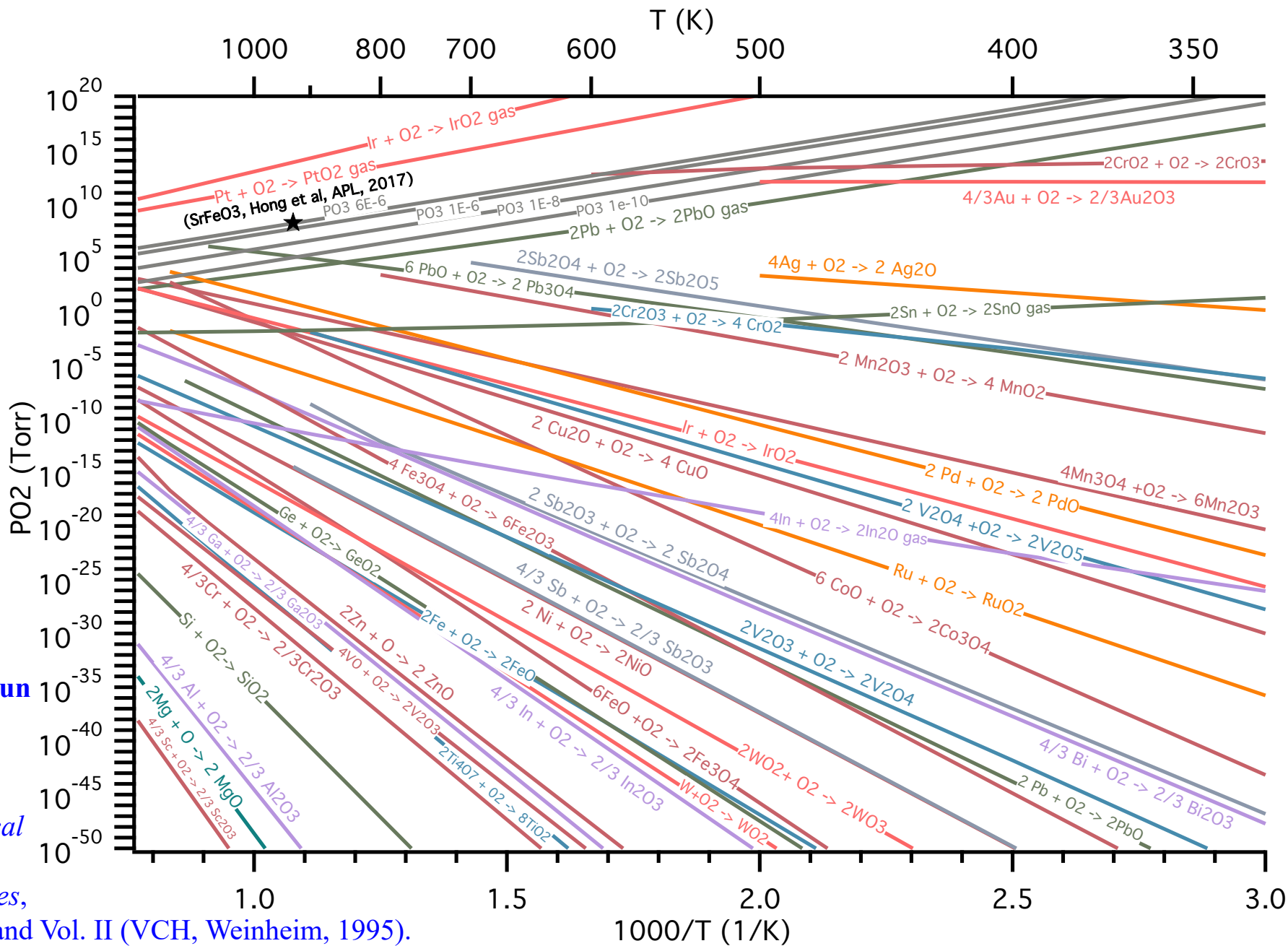


O₂ Needed to Oxidize Constituents



data from I. Barin, *Thermochemical Data of Pure Substances*,
3rd Ed., Vol. I and Vol. II (VCH, Weinheim, 1995).

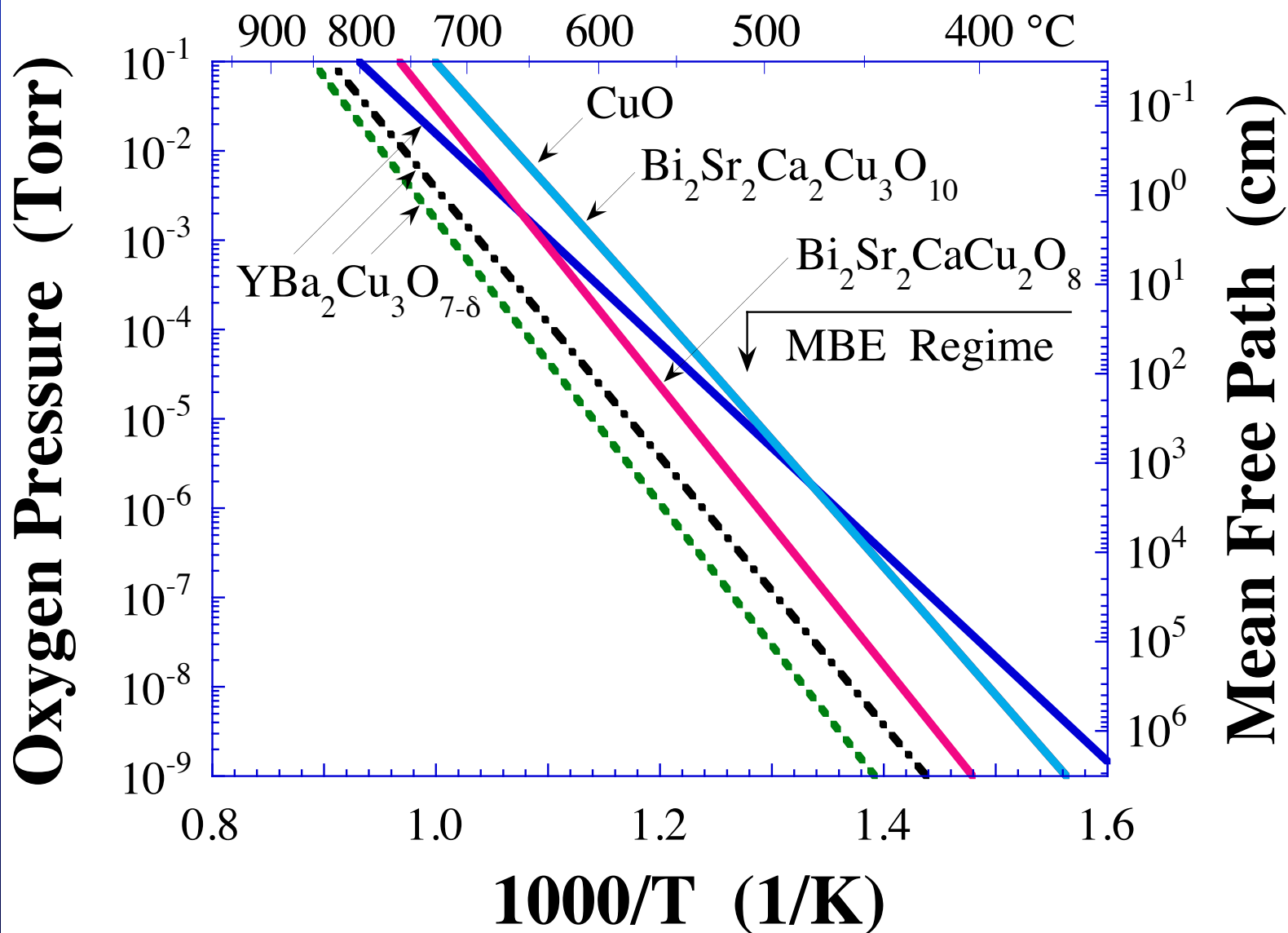
O₂ Needed to Oxidize Constituents



plot by Jake Sun

data from
I. Barin,
*Thermochemical
Data of
Pure Substances*,
3rd Ed., Vol. I and Vol. II (VCH, Weinheim, 1995).

O₂ Needed to Oxidize Cuprates



O₃ Activity by Thermodynamics

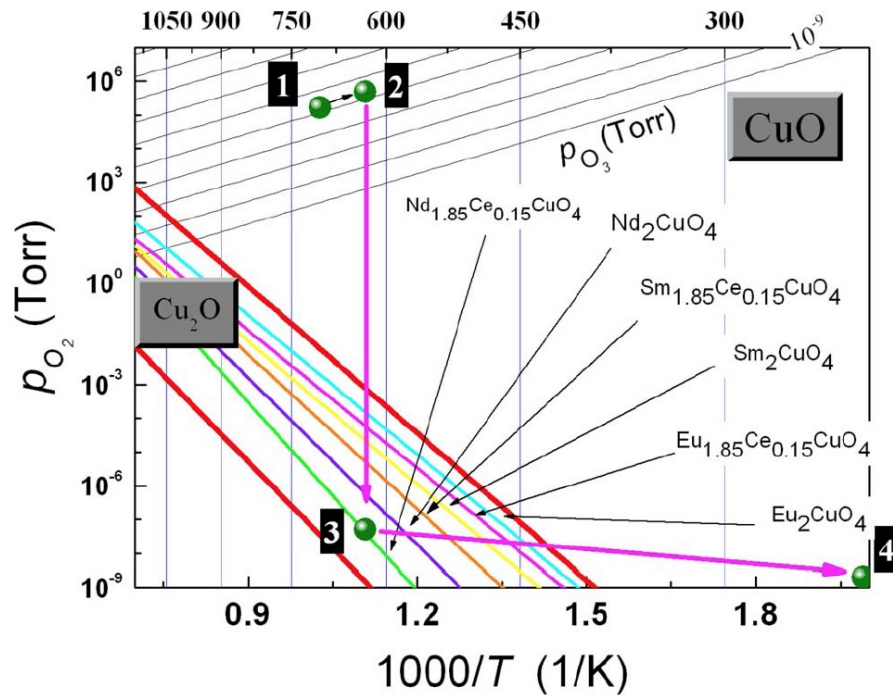
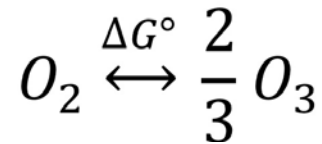


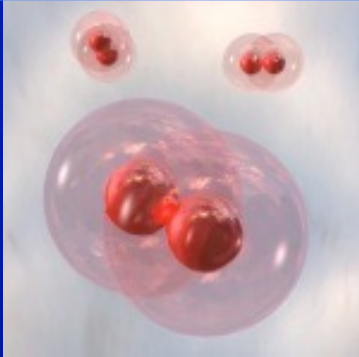
FIG. 1. (Color online) Typical thermodynamic phase stability diagram for electron-doped cuprates. Stability lines for CuO and Cu₂O have been calculated using the commercially available program MALT®. Additionally, the equilibria oxidizing potential lines for ozone and oxygen are calculated. The numbered points describe a typical growth of the thin film. The border lines for the different copper valencies are thick red colored. Between them, all experimentally established stability lines for the T'-structure compounds are lying. Points 1 and 2 represent the growth followed by annealing in vacuum (point 3) and afterwards cooled down to point 4.



$$P_{O_2} = P_{O_3}^{2/3} e^{\left(\frac{\Delta G^\circ}{R T_{sub}}\right)}$$

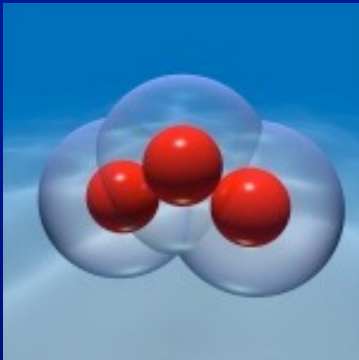
Activity of O₃ is ~10¹²
higher than O₂ at
typical T_{sub}

Oxygen vs. Ozone



Oxygen:

- Easy to use – directly from the cylinder
- Depending on material, films are oxygen-deficient



Ozone from ozone generator:

- Around 15 wt% O₃ in O₂
- As O₃ easily decomposes, one O₃ is similar to one O radical
- Higher wt% not achievable, saturation of O₃ concentration



Distilled ozone:

- Can provide 80-100 wt% pure O₃
- Better film oxidation, wider process window
- But: Gas is explosive above ~10 Torr (absolute), liquid is explosive and shock-sensitive

Vapor Pressure Oxygen vs. Ozone

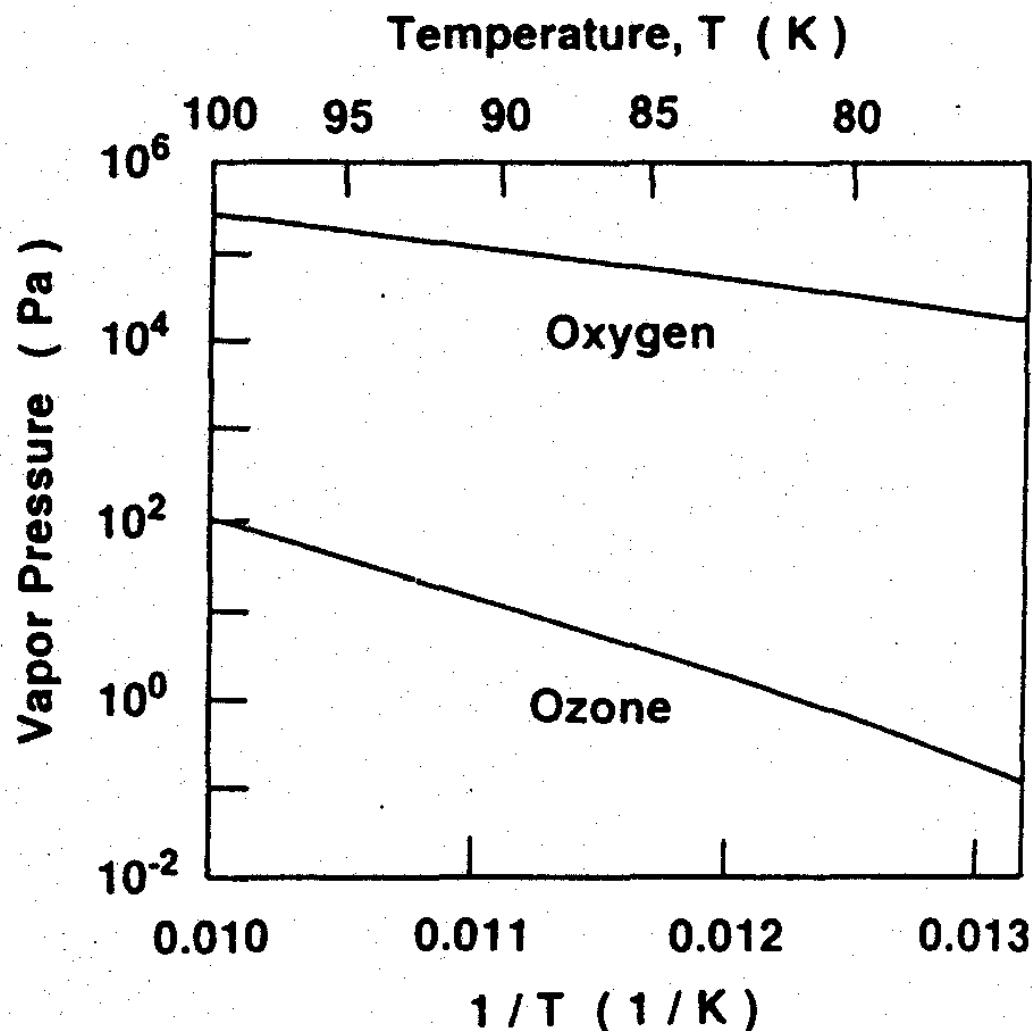


FIG. 4. Vapor pressure of ozone and oxygen as a function of temperature.

Ozone Safety Concerns

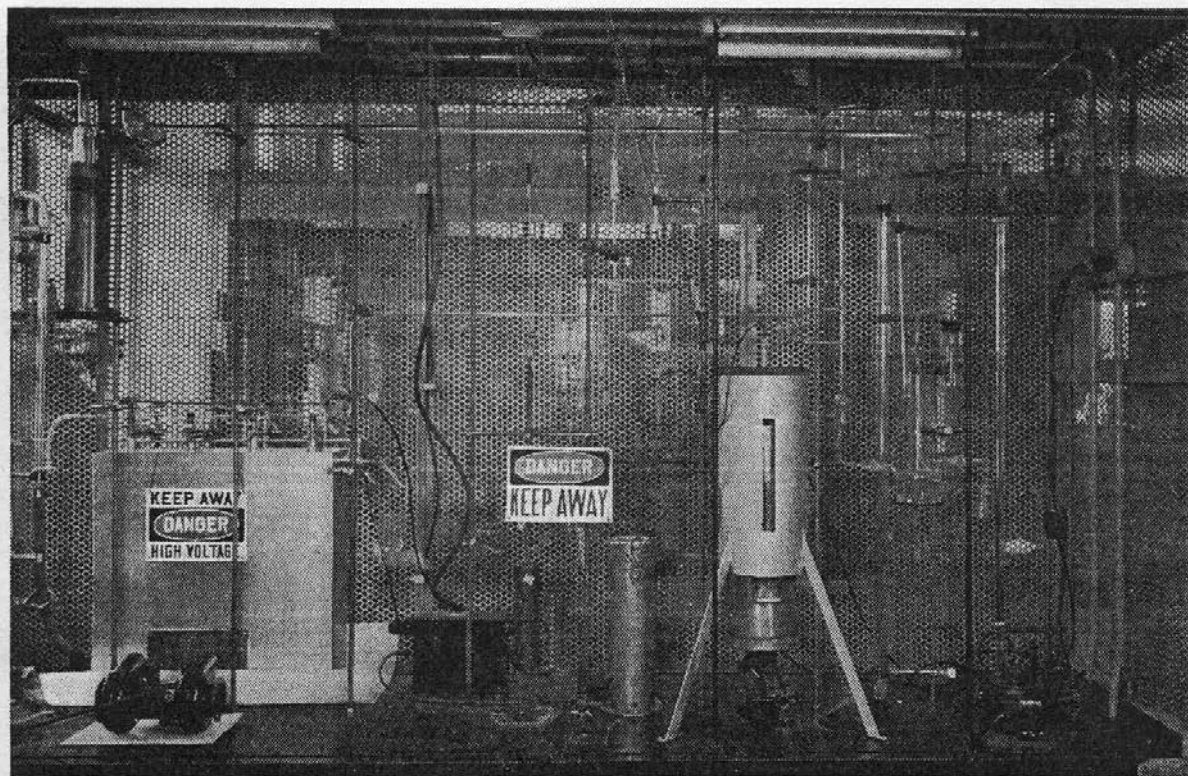


Figure 4. Ozone system

A.C. Jenkins

“Laboratory Techniques for Handling High-Concentration Liquid Ozone,” in:
Ozone Chemistry and Technology
Vol. 21 of Advances in Chemistry Series
(American Chemical Society, Washington, D.C., 1959) pp. 13-21.

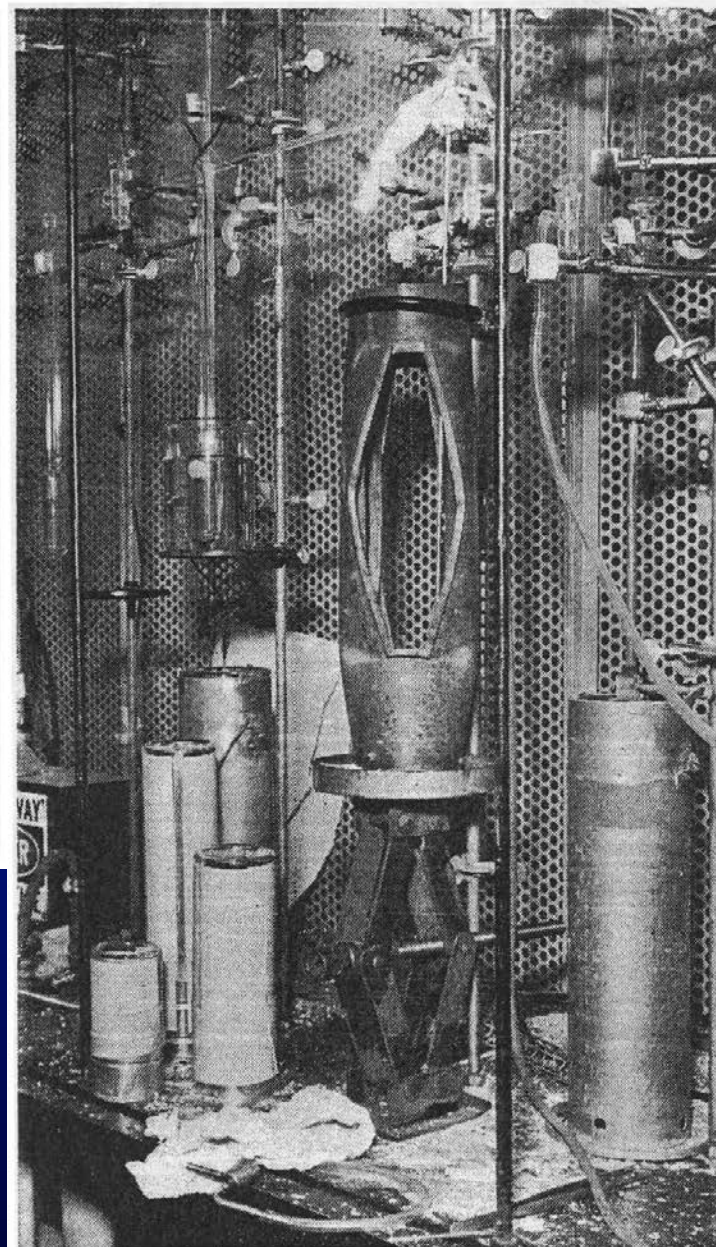


Figure 5. Apparatus after explosion

Ozone in Silica Gel (Union Carbide)

Separation of Ozone from Oxygen by a Sorption Process

G. A. COOK, A. D. KIFFER, C. V. KLUMPP, A. H. MALIK, and L. A. SPENCE

Research and Development Laboratory, Linde Co., A Division of Union Carbide Corp.,
Tonawanda, N. Y.

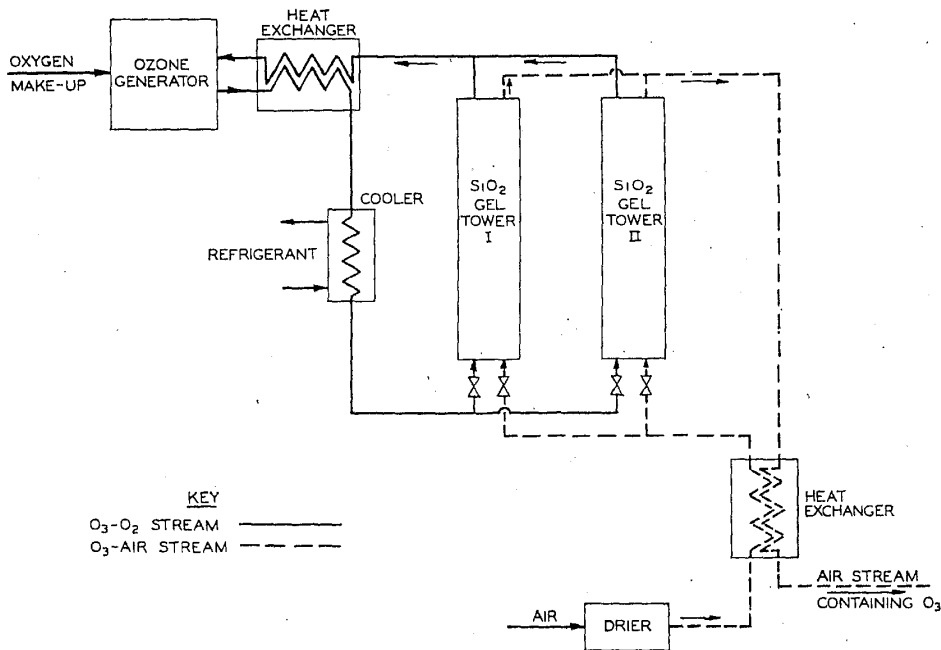


Figure 7. Simplified flow diagram for two-stage transfer process

Ozone is separated from oxygen by adsorption on refrigerated silica gel, followed by desorption, either in pure form at reduced pressure, or diluted by air, nitrogen, argon, or other gas not strongly adsorbed on silica gel. This is a practical method, free from hazard when correctly performed.

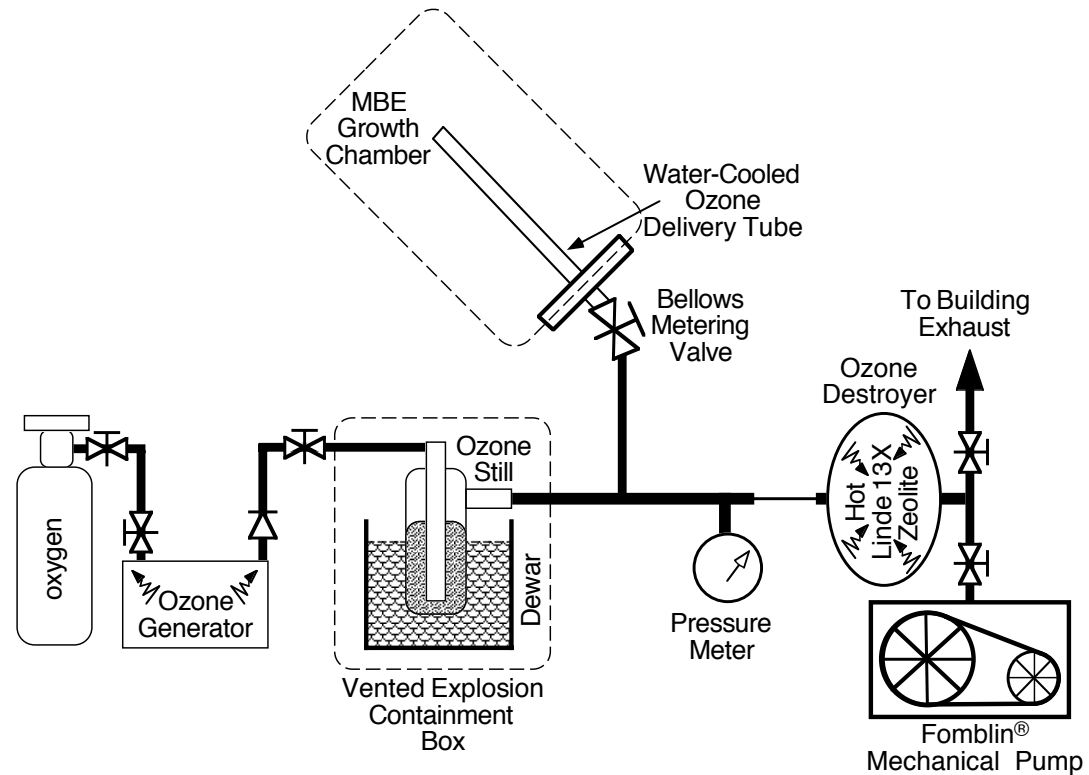
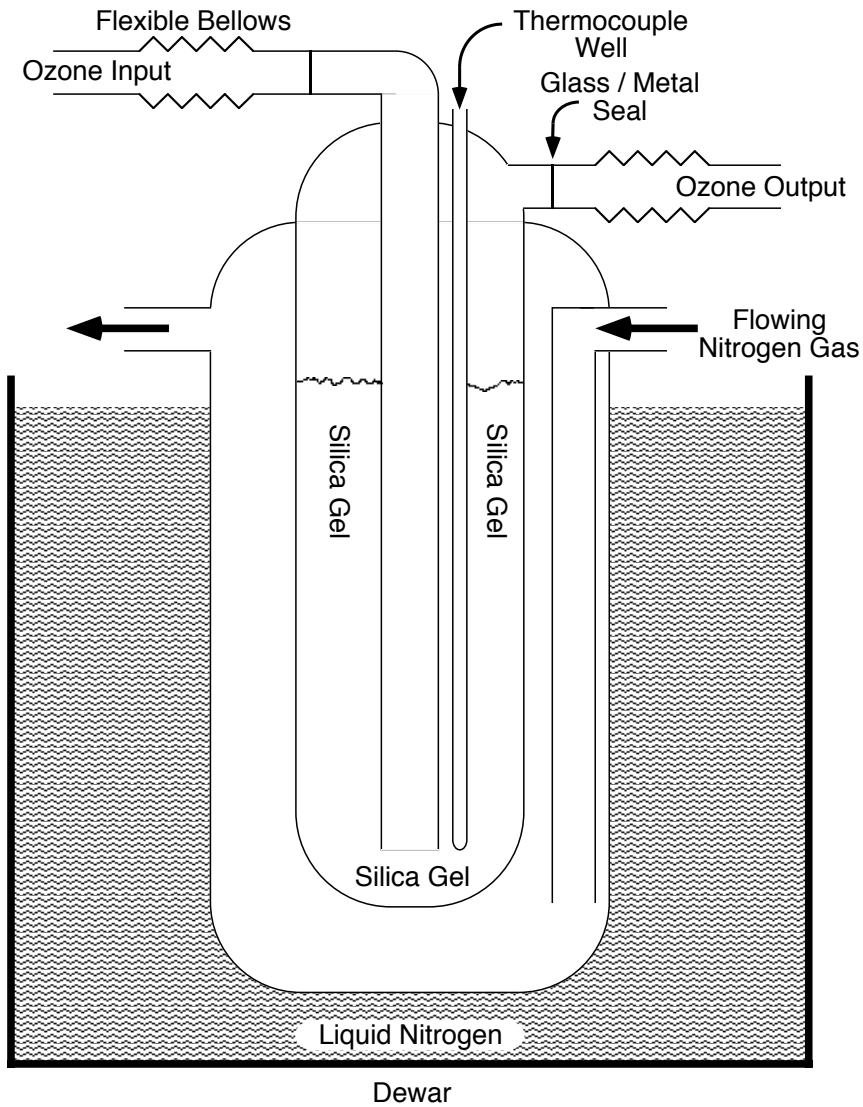
G.A. Cook, A.D. Kiffer, , C.V. Klumpp, A.H. Malik,
and L.A. Spence,

“Separation of Ozone from Oxygen
by a Sorption Process,” in:

Ozone Chemistry and Technology,

Vol. 21 of Advances in Chemistry Series, (American
Chemical Society, Washington, D.C., 1959) pp. 44-52.

Ozone in Silica Gel



Process Control



- Safety committee requirements led to development of fully integrated process controller
- Controller monitors all process equipment and parameters
- Countermeasures if close to critical limit
- Self-test of equipment before process start
- Fully automated operation
- No need to manually watch ozone process, user can focus on MBE growth!!!



Ozone System Passivation

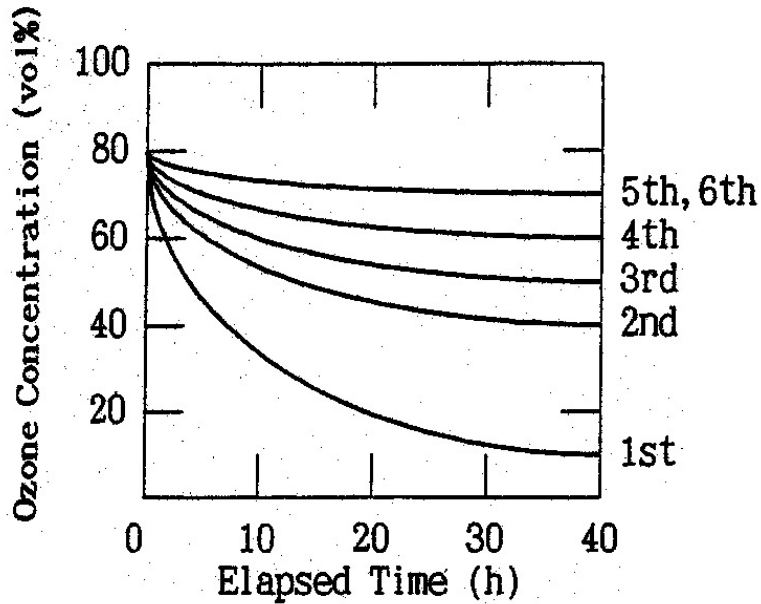


Fig. 2. Ozone concentration decay during ozone passivation.

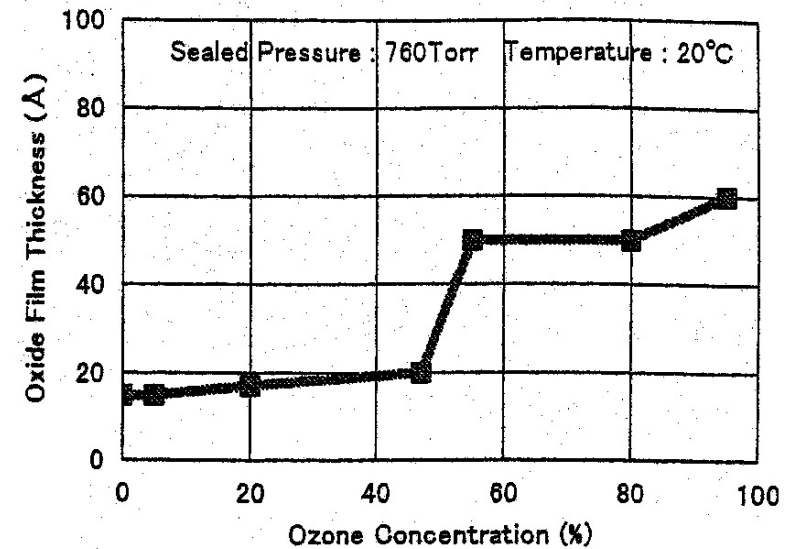


Fig. 4. Relationship of ozone concentration with thickness of passivated film formed at atmospheric pressure and 20°C.

Pros and Cons of Ozone

- Pros

- Excellent Oxidant
($>10^3$ (experiment) to $<10^{12}$ (thermo) more powerful than O_2)
- 80% Ozone (+20% O_2) delivered to the Substrate
- No Energetic Species (thermal ozone beam)
- Clean (lower in contaminants than plasma beam)

- Cons

- Safety (Ozone still issues)
- Safety (Pump issues)
- Need Ozone-Compatible UHV Leak Valve
- Need to Passivate Ozone System

If you want to grow EuO by MBE, what oxidant should you use?

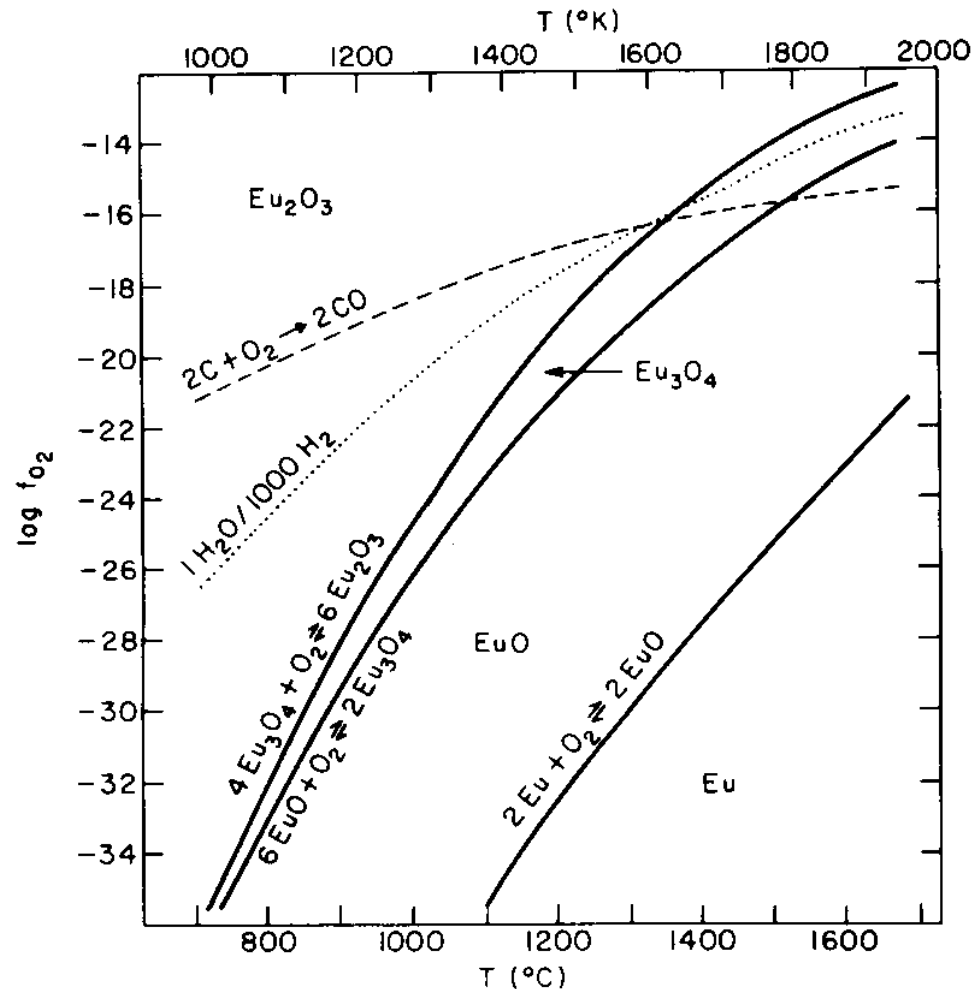


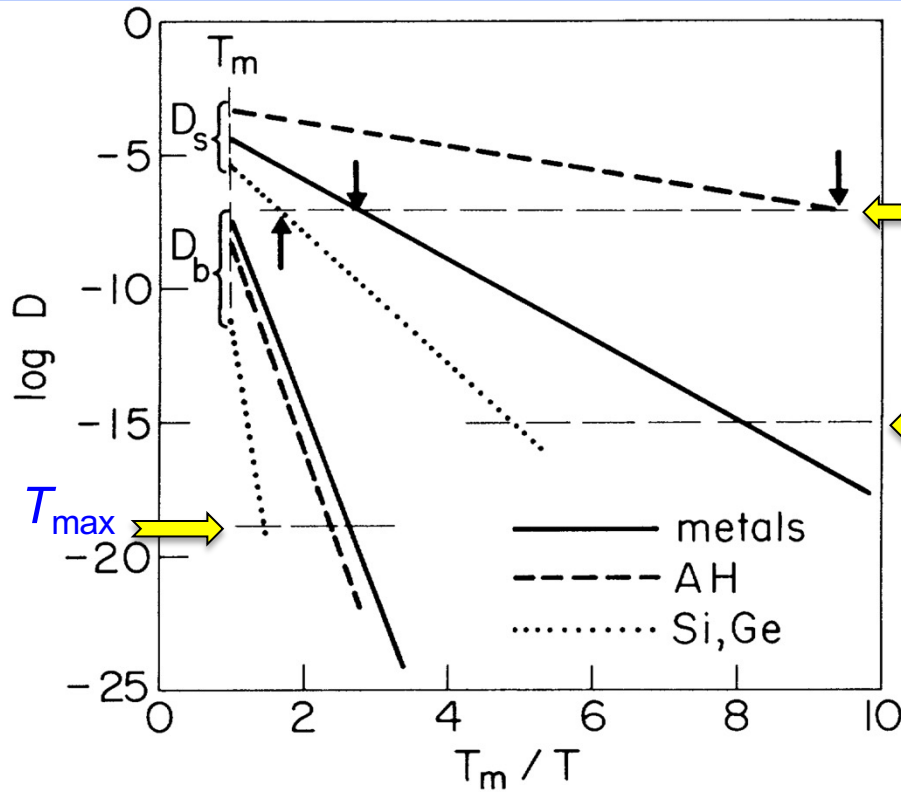
Fig. 1. Plot of $f_{O_2}(T)$ for oxidation reactions of Eu, EuO, and Eu_3O_4 and for C to CO and H_2 with 1 part/1000 H_2O .

G.J. McCarthy
 "Oxygen-Fugacity-Temperature Diagram for the Eu-O System,"
Journal of the American Ceramic Society **57** (1974) 502.

Nuts and Bolts of Oxide MBE

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- Optimal T_{sub}
- MBE System
- MBE Sources
- Crucibles

Surface vs. Bulk Diffusion



Assuming growth rate of
0.1 monolayer/sec

T_{min} for smooth epitaxial films
(growth by step propagation)

T_{min} for epitaxy

Optimal Growth Temperatures

$$0.55 < \frac{T_{sub}}{T_{melt}} < 0.7 \text{ for semiconductors}$$

$$0.35 < \frac{T_{sub}}{T_{melt}} < 0.4 \text{ for metals}$$

$$0.1 < \frac{T_{sub}}{T_{melt}} < 0.4 \text{ for simple ceramics}$$

FIG. 6. Diagram showing deduced global dependences of surface and bulk diffusion coefficients, D_s and D_b , on T_m/T for metals (solid lines), elemental semiconductors (dotted lines), and salts (dashed lines). The construction is described in the text. Smooth flat interfaces generally require $D_s \gtrsim 10^{-8} - 10^{-7}$ cm^2/sec , which fixes the lowest growth temperatures (arrows) as $\sim 3T_m/8$, $0.55T_m$, and $0.1T_m$ in the three cases. RHEED oscillations are expected for $D_s \gtrsim 10^{-15}$ cm^2/sec and bulk interdiffusion for $D_b \gtrsim 10^{-19}$ cm^2/sec .

M.H. Yang and C.P. Flynn

Physical Review Letters **62** (1989) 2476-2479.



Universal Diffusion Behavior of Metals

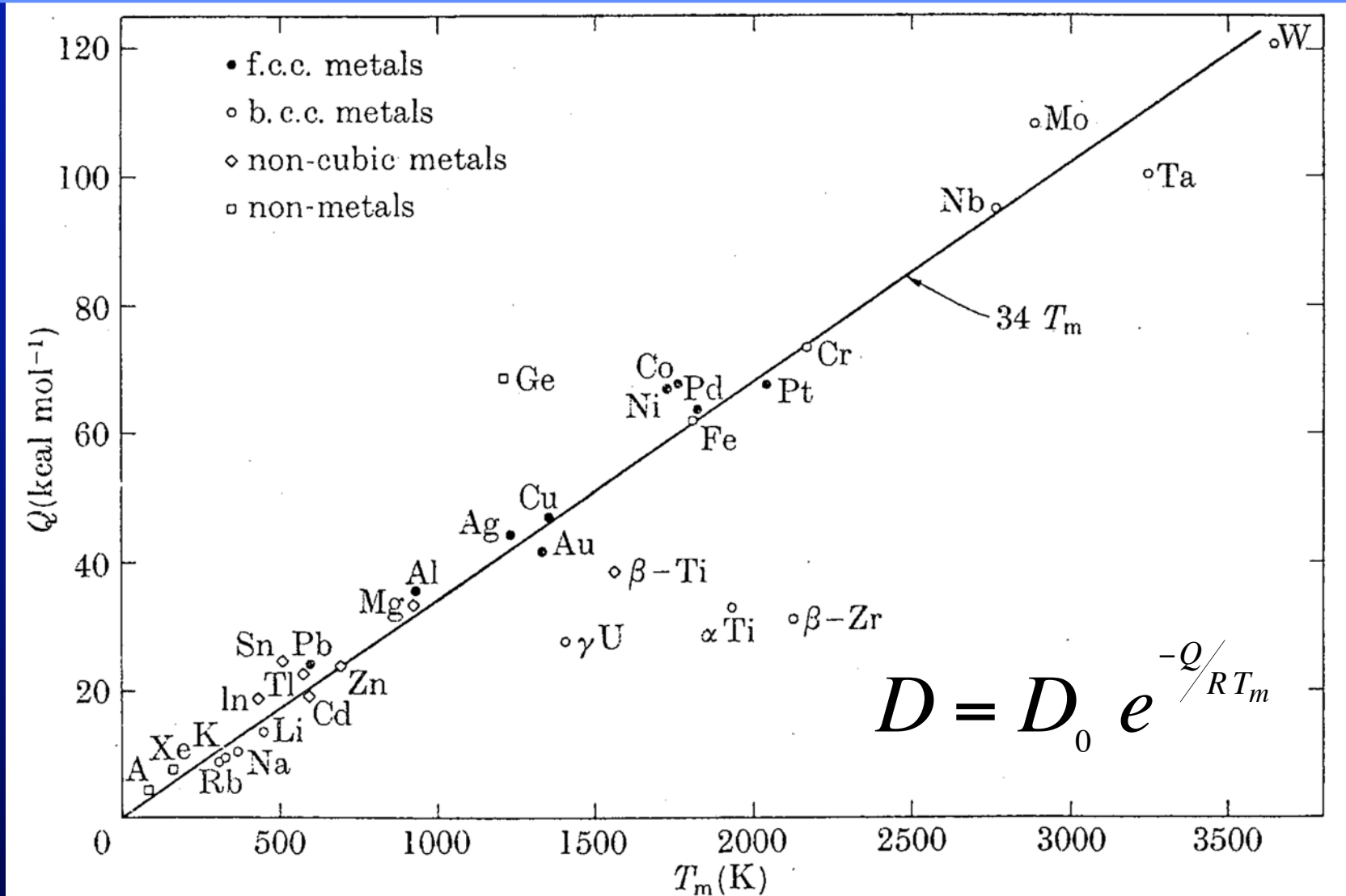
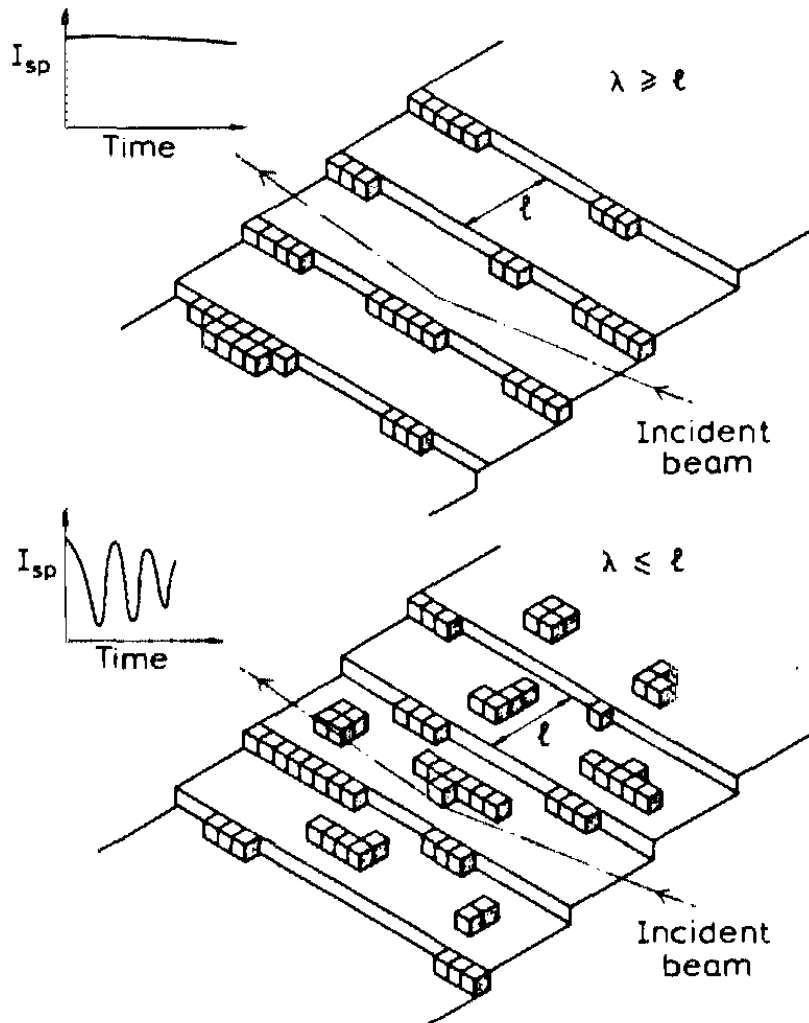


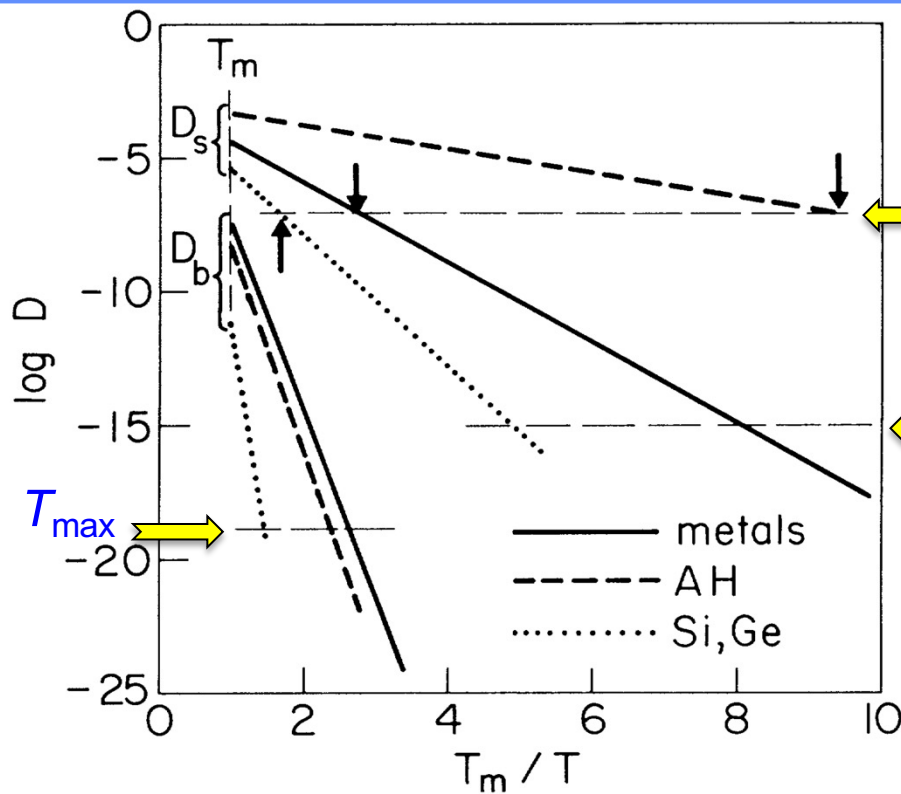
FIG. 14.31. The correlation between Q and T_m .

Determining Surface Diffusion from RHEED Oscillations



J.H. Neave, P.J. Dobson,
B.A. Joyce, and J. Zhang,
Applied Physics Letters **47**
(1985) 100-102.

Surface vs. Bulk Diffusion



Assuming growth rate of
0.1 monolayer/sec

T_{min} for smooth epitaxial films
(growth by step propagation)

T_{min} for epitaxy

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Physical Review Letters **62** (1989) 2476-2479.



Surface Energy Considerations

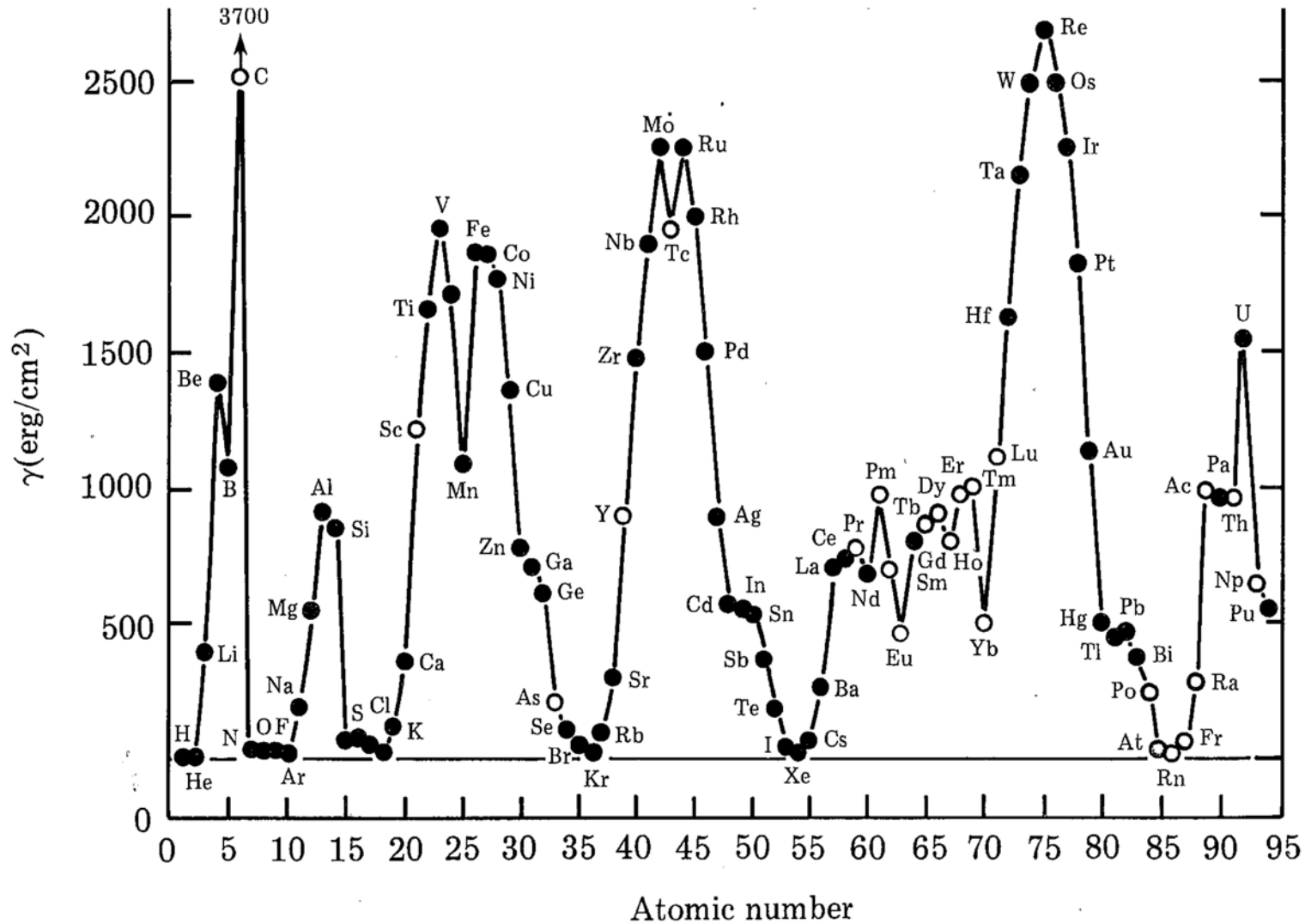


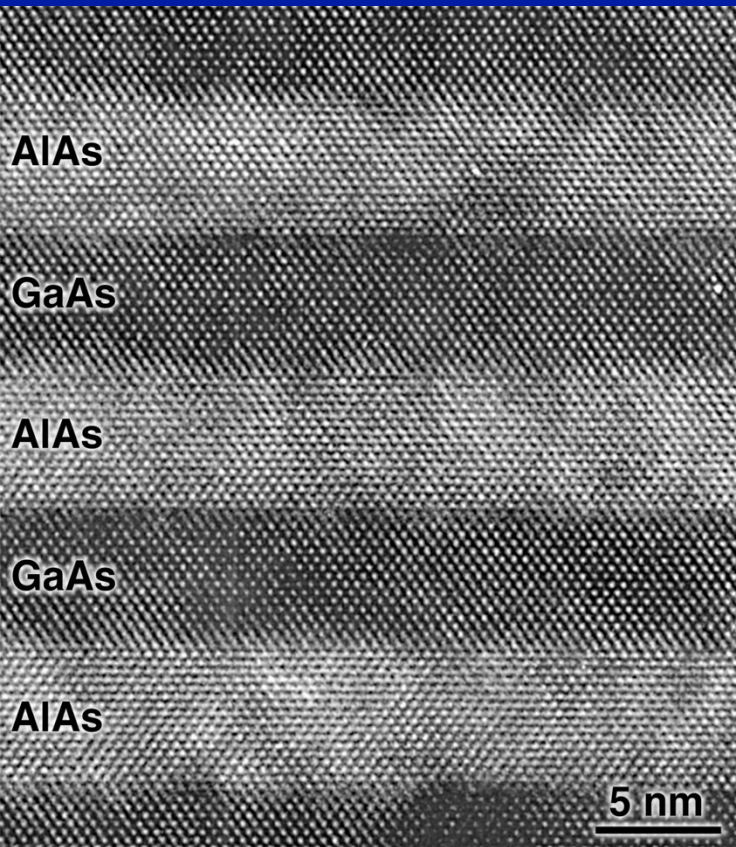
FIGURE 2.7 Surface tension of elements in the liquid phase (from Zangwill, 1988).

K.-N. Tu, J.W. Mayer, and L.C. Feldman,

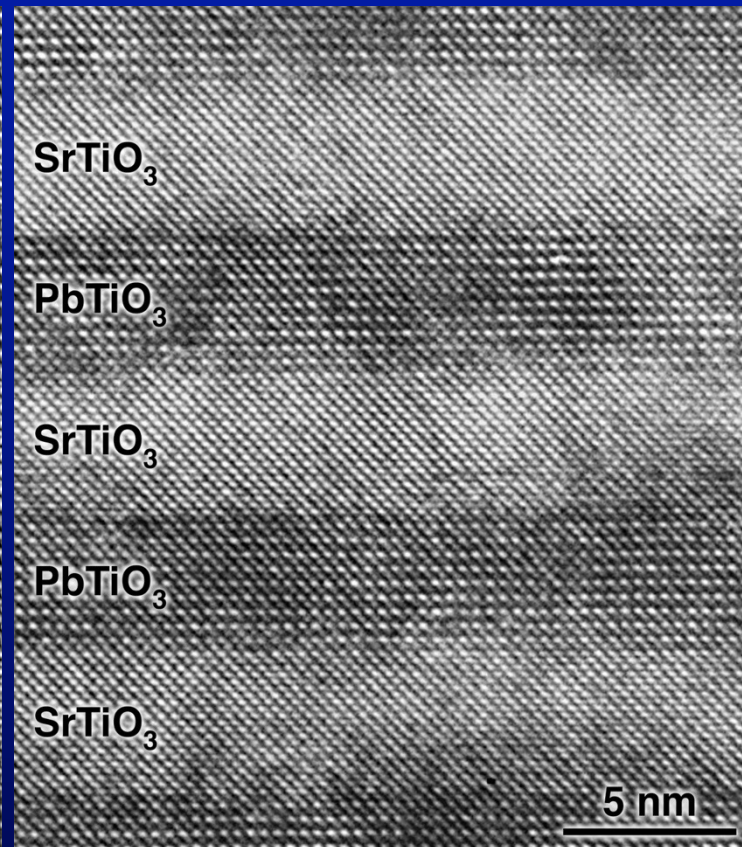
Electronic Thin Film Science for Electrical Engineers and Materials Scientists
(Macmillan, 1992).

TEM of MBE-Grown Superlattices

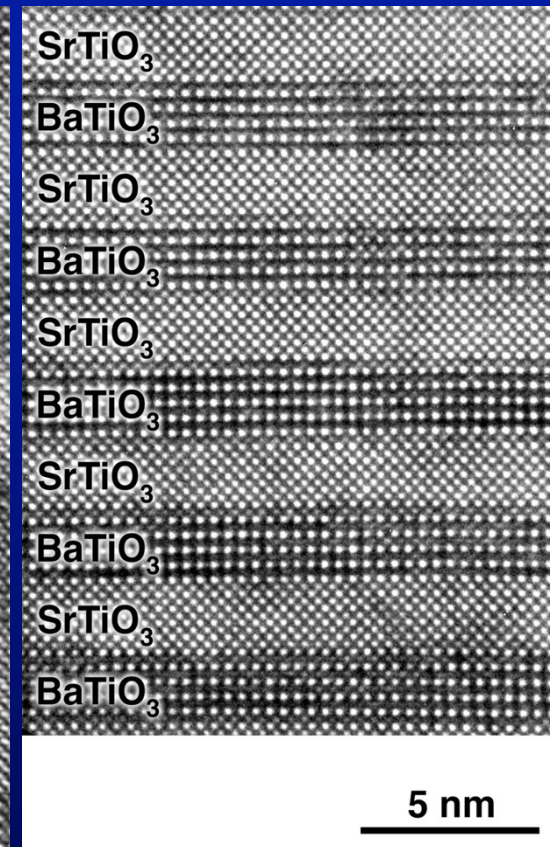
AlAs / GaAs



PbTiO₃ / SrTiO₃



BaTiO₃ / SrTiO₃



A.K. Gutakovskii *et al.*,
Phys. Stat. Sol. (a) **150** (1995) 127.

 PARADIM

C.D. Theis
(1st Generation Schlom Group)
HRTEM—Pan Group (Michigan)

D.G. Schlom *et al.*, Mater. Sci. Eng. B **87** (2001) 282.

J.H. Haeni
(2nd Generation)



From the observed
morphology,
which likely has the
higher surface energy?

(a) GaAs

(b) AlAs

(c) They appear to have the same
surface energies

Thermodynamic Considerations

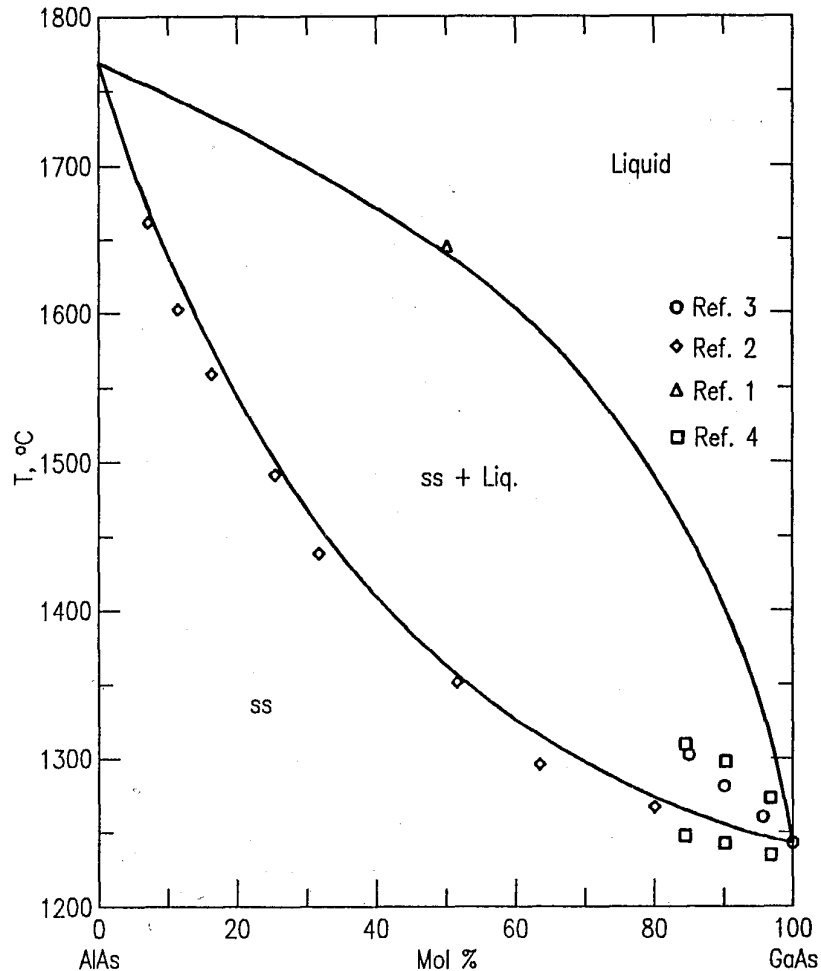


Fig. 8343—Pseudobinary system AlAs-GaAs.

K. Y. Ma, S. H. Li, and G. B. Stringfellow, "P, As, and Sb Phase Diagrams", Special Report to the Standard Reference Data Program, National Institute of Standards and Technology; Gaithersburg, Maryland (1987).

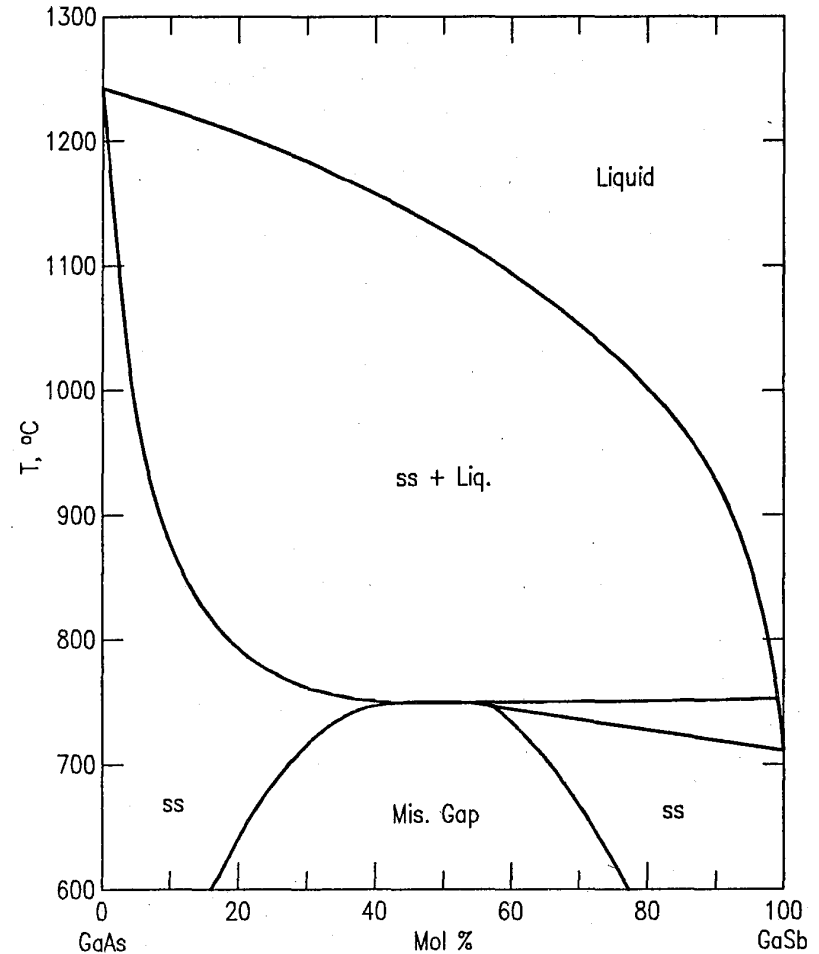


Fig. 8362—Pseudobinary system GaAs-GaSb. Calculated diagram.

K. Y. Ma, S. H. Li, and G. B. Stringfellow, "P, As, and Sb Phase Diagrams", Special Report to the Standard Reference Data Program, National Institute of Standards and Technology; Gaithersburg, Maryland (1987).

Thermodynamic Considerations

Increased Interface Roughness and Clustering at Non-Optimal Growth Conditions

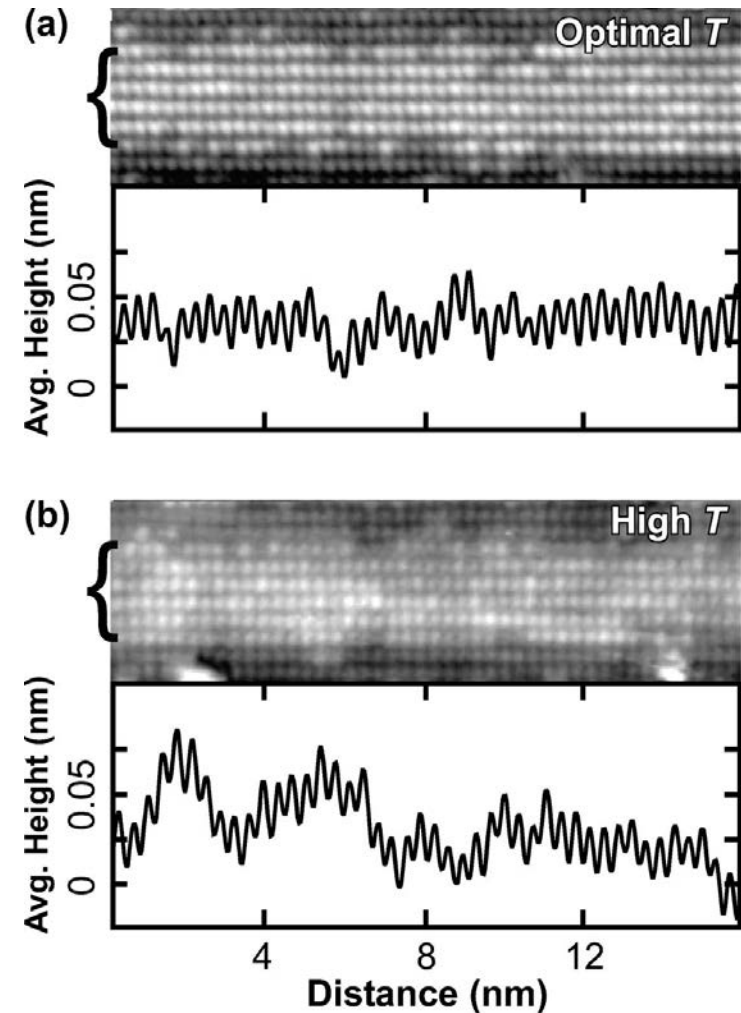
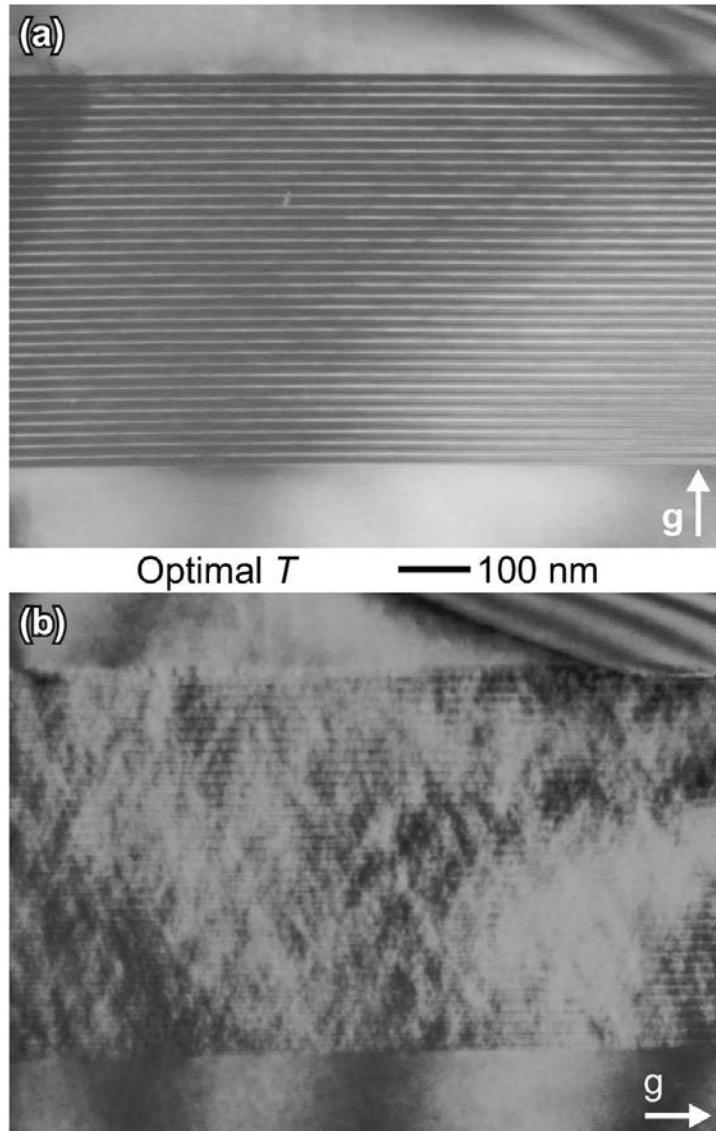
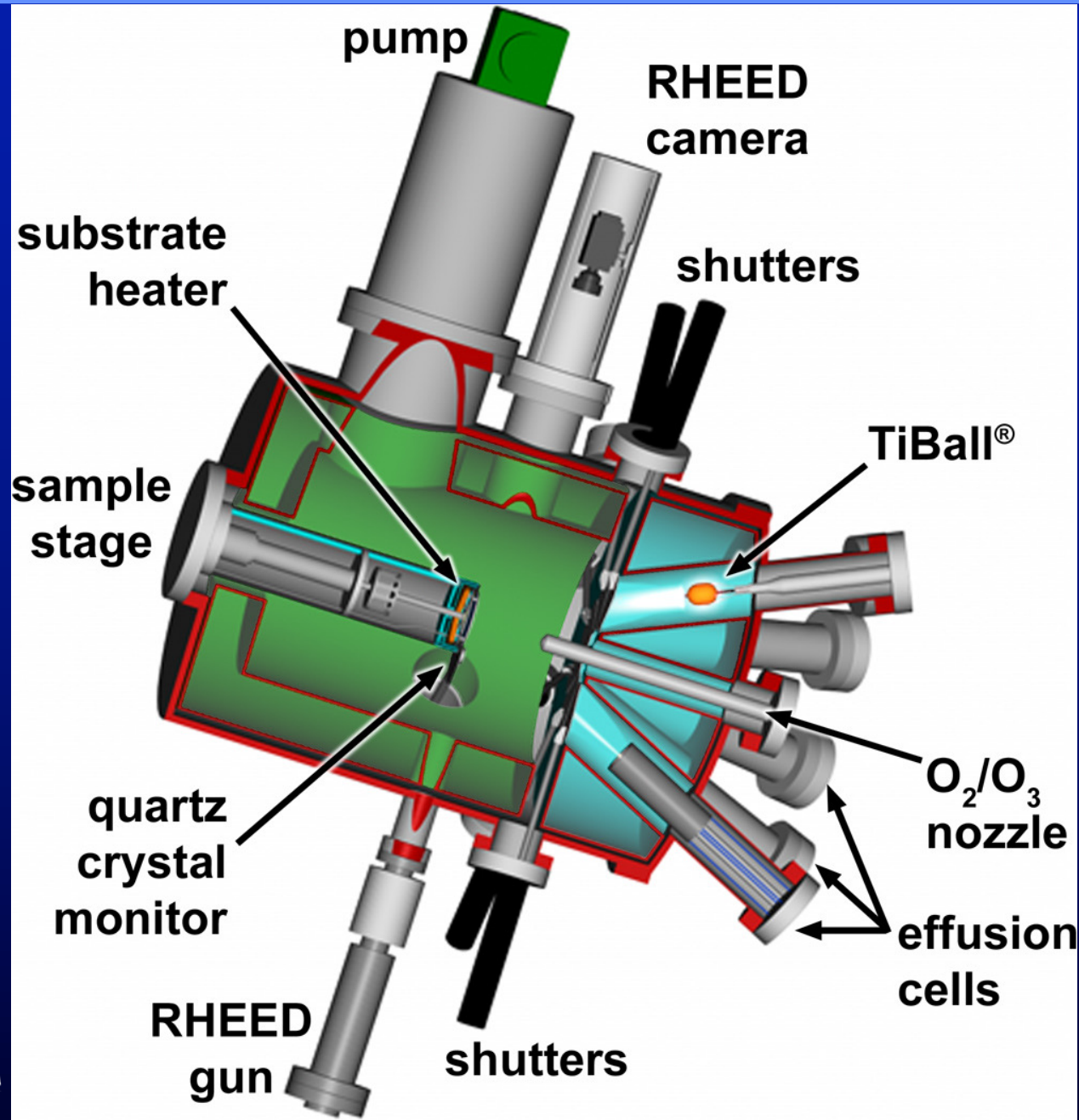


FIG. 6. XSTM images and average-height profiles for InGaSb-alloy layers in an (a) optimal- and (b) high-temperature sample. (a) -2.0 V, 50 pA and (b) -2.5 V, 0.5 nA.

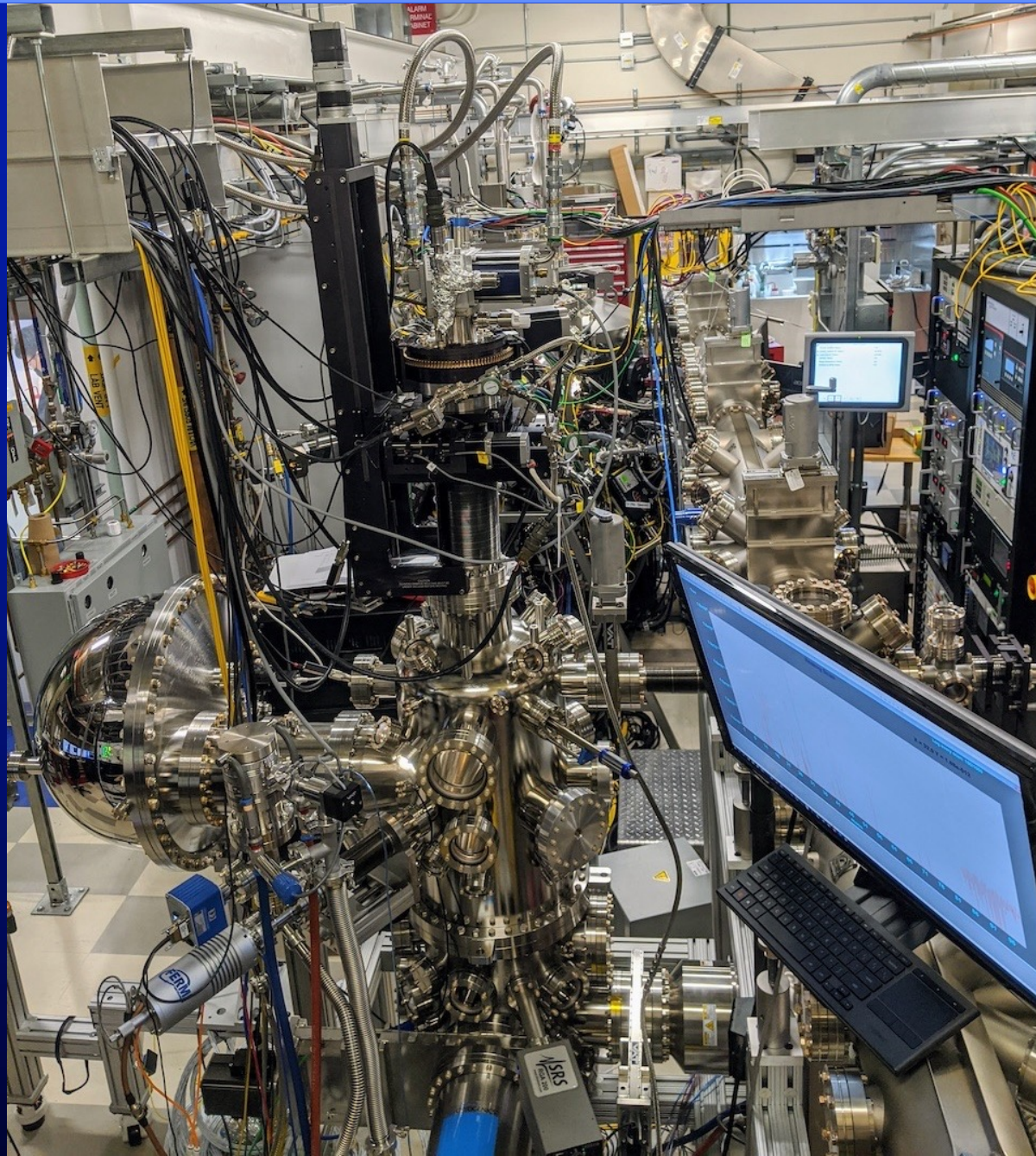
Nuts and Bolts of Oxide MBE

- Mean Free Path (maximum P_{O_2})
- Minimum P_{O_2} , need for P_{O_3}
- Optimal T_{sub}
- **MBE System**
- **MBE Sources**
- **Crucibles**

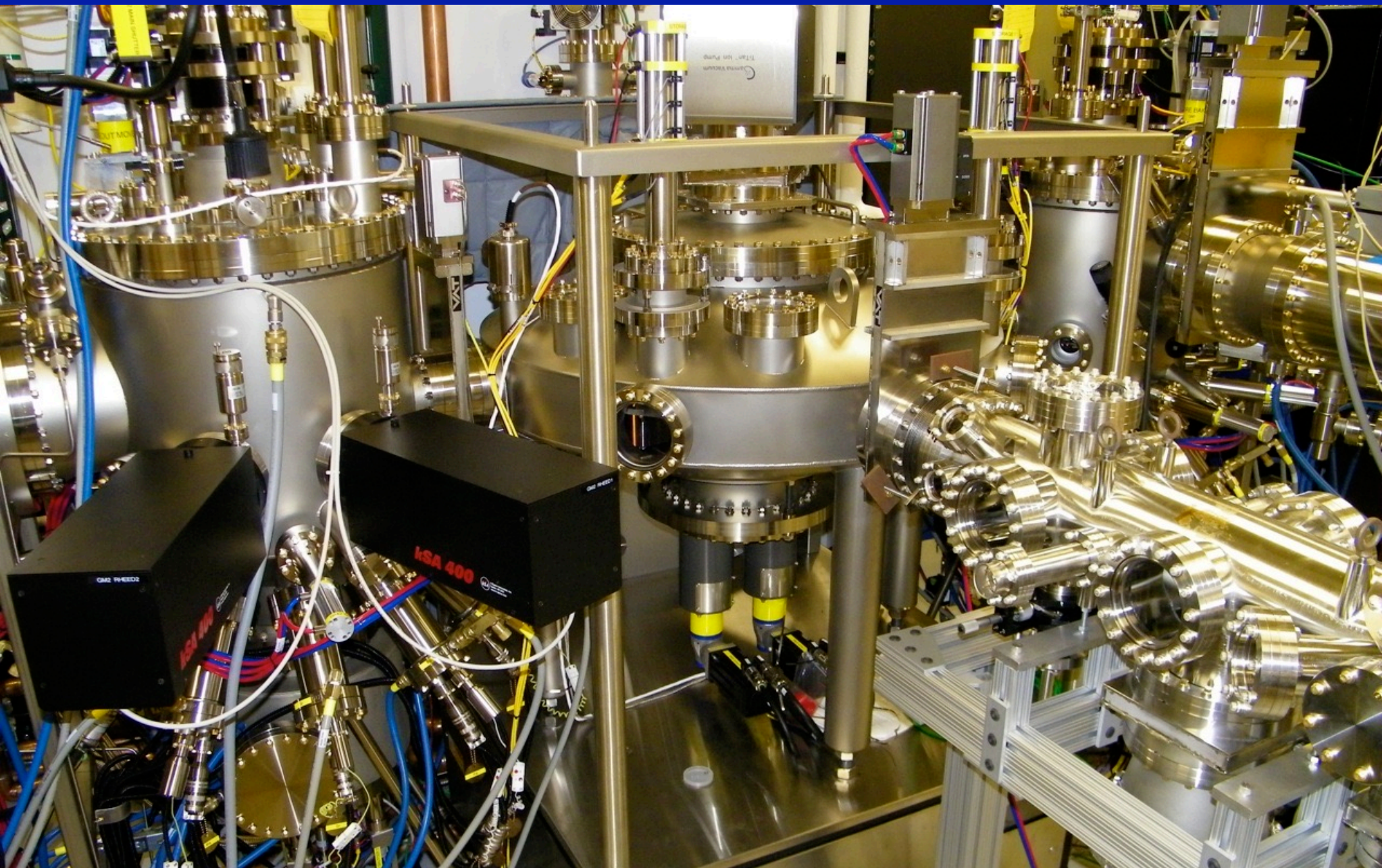
Oxide MBE System



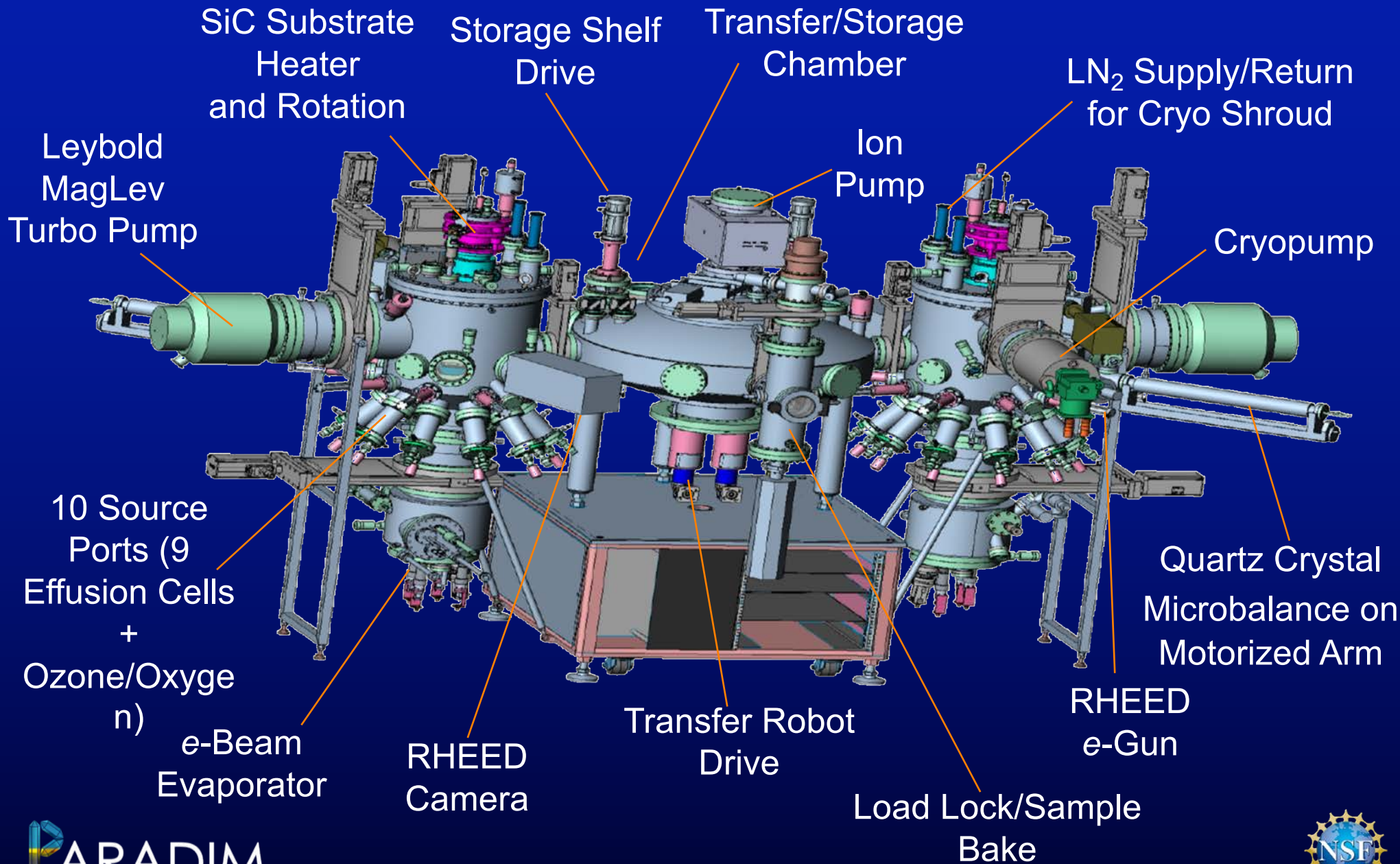
PARADIM MBE + ARPES



Oxide MBE



Automated Veeco GEN10 Oxide MBE

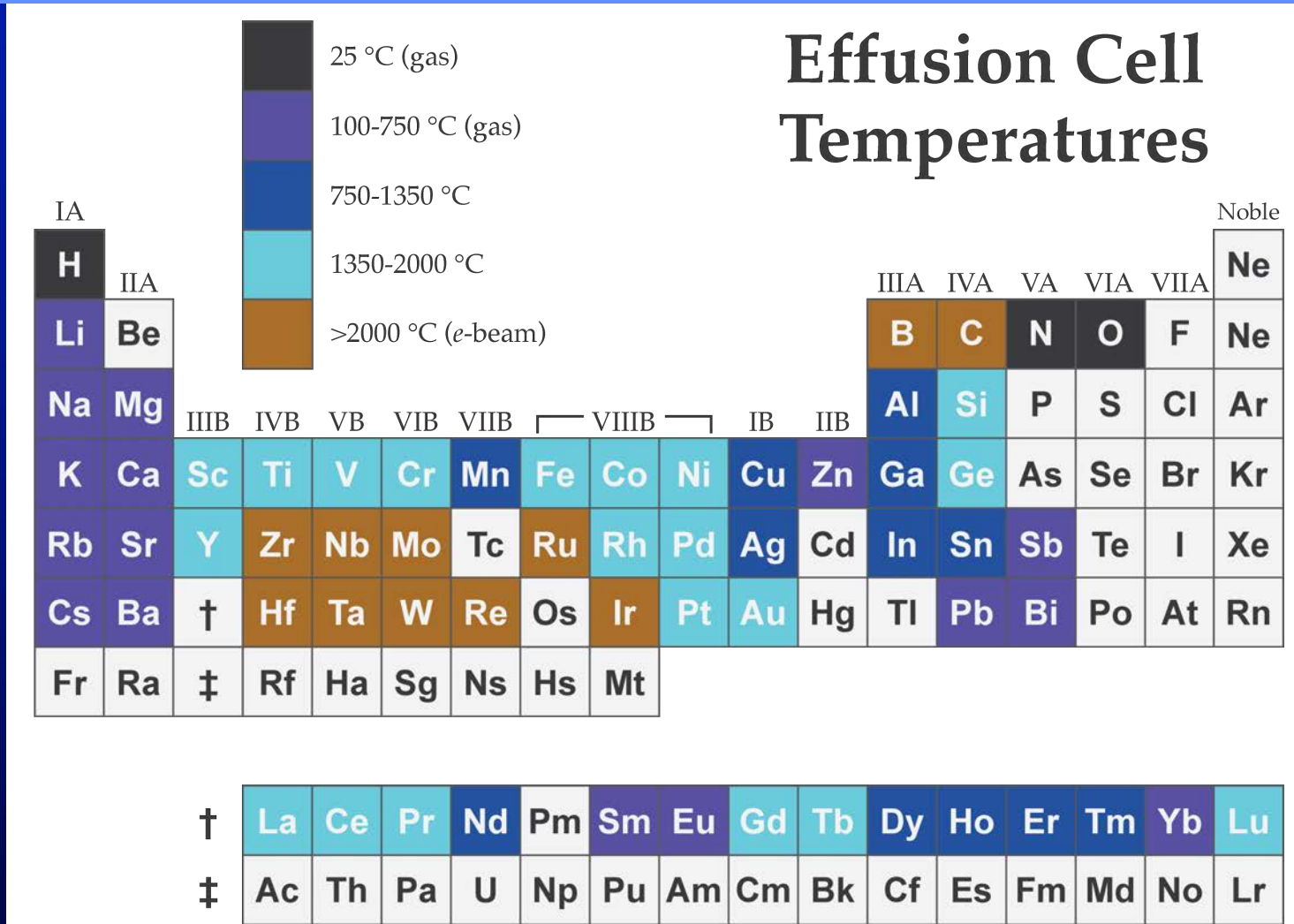


Sources for Oxide MBE

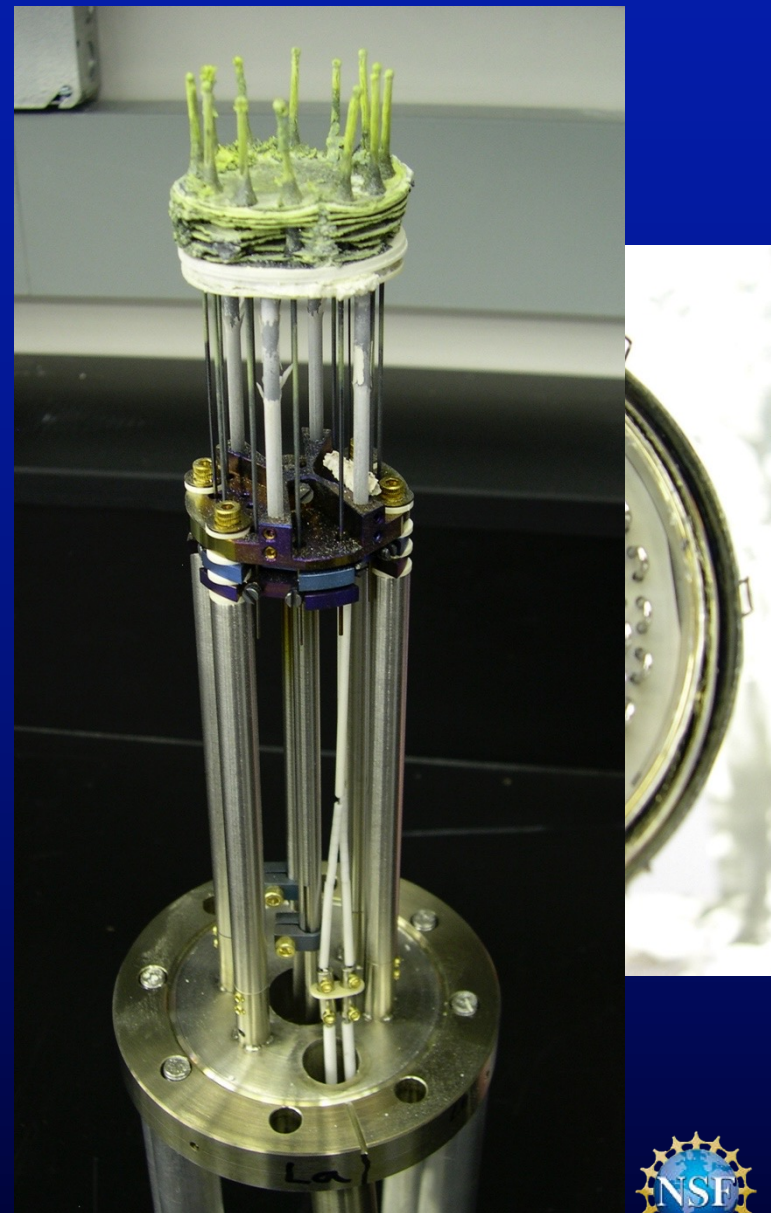
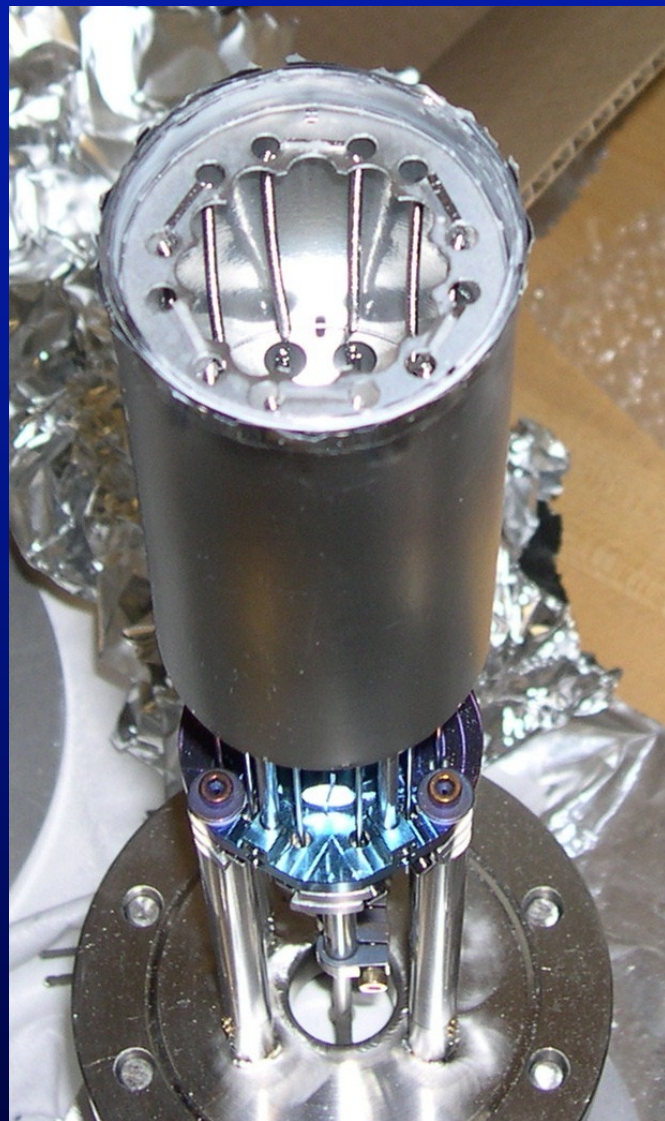


- **Effusion cell**
(resistively heated thermal evaporators, up to 2000°C), material in crucible
- **Ti-Ball™ source**
titanium sphere with resistive heater inside
- **e-gun evaporator**
for extremely low vapor pressure materials (W, Ru, etc.)

MBE Effusion Cells for Different Temperatures



MBE Effusion Cells

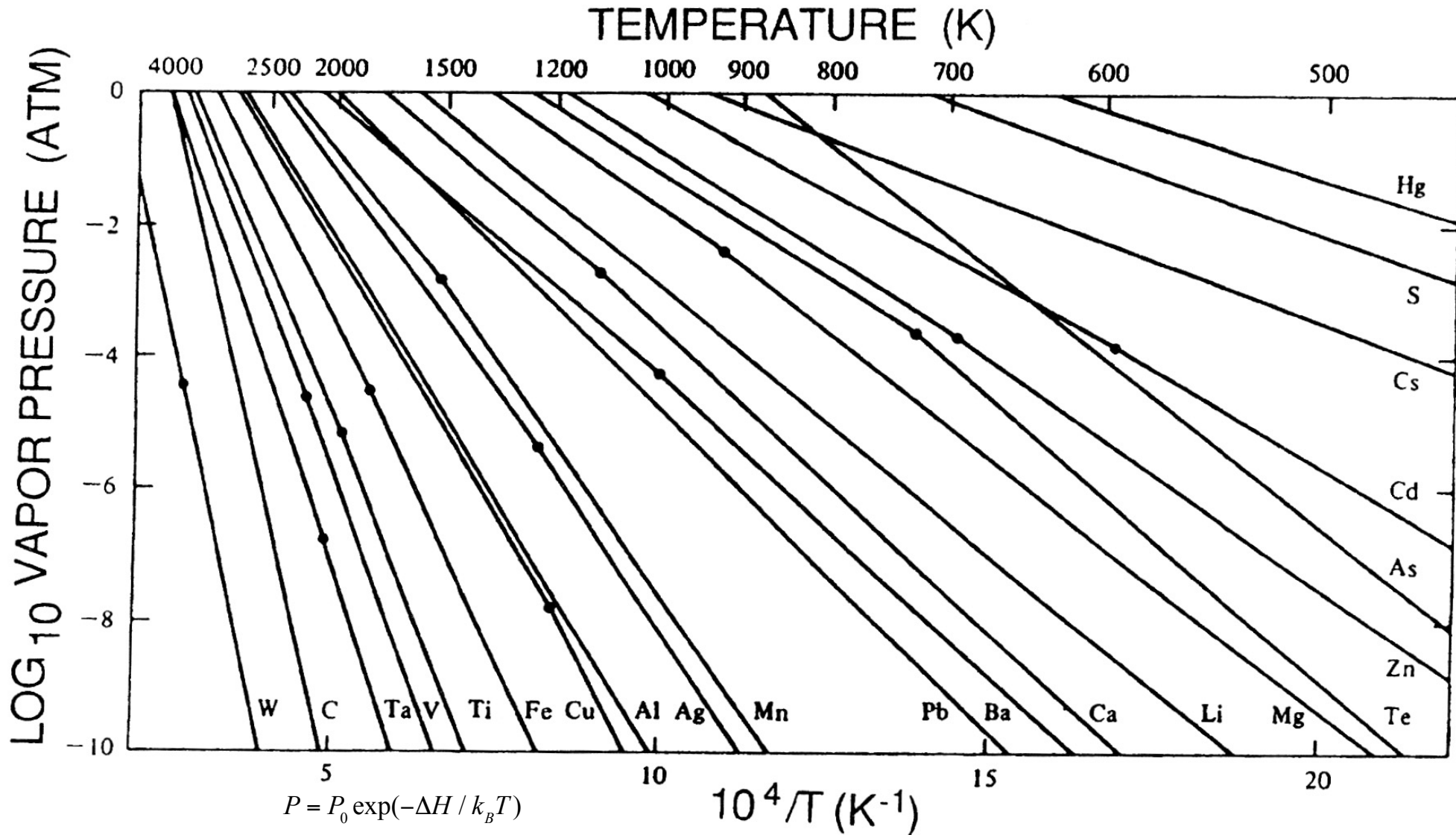


Differentially Pumped Effusion Cells



Enable stable fluxes at distilled ozone pressures up to 1×10^{-5} Torr
Can change or refill sources without venting entire MBE

Arrhenius Plot of Vapor Pressure



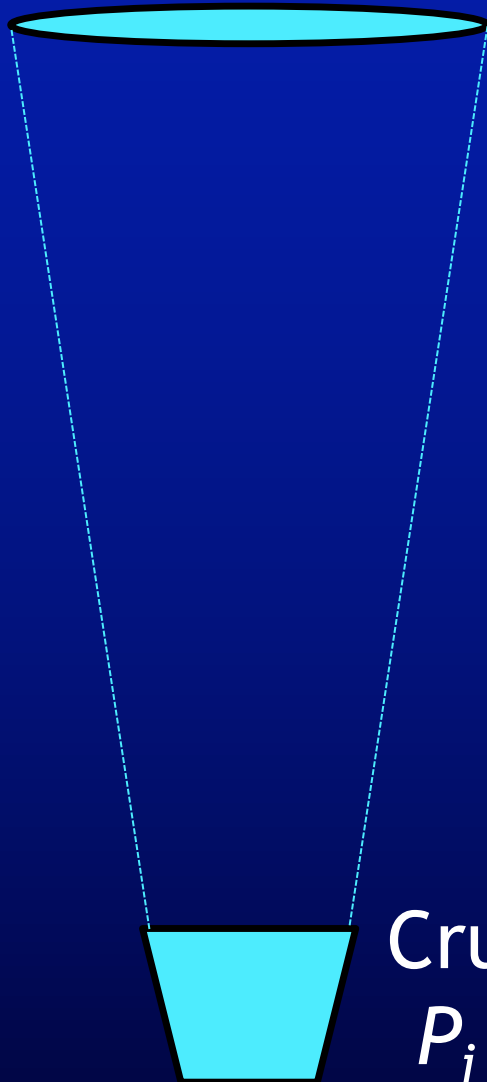
$$\ln P = \ln P_0 - \left(\frac{\Delta H}{k_B} \right) \cdot \left(\frac{1}{T} \right)$$

so plot $\log(P)$ vs $1/T$: straight line if ΔH is constant
(note small change in slope at melting point)

If your desired flux of Sr is 30% higher than your measured flux or Sr, how would you go about calculating how much you need to increase the temperature of the Sr effusion cell to get the desired flux?

What Vapor Pressure Needed?

Substrate (growth rate = 0.1 monolayers/s)



Crucible

$P_i = ???$

$$\Phi_{Sr} = (0.1) \frac{1 \text{ Sr atom}}{(3.905 \text{ \AA})^2} \text{ s}^{-1} = 6.6 \times 10^{13} \frac{\text{atoms}}{\text{cm}^2 \text{ s}} \text{ for SrTiO}_3$$

From kinetic theory of gases:

$$\Phi = \frac{P}{\sqrt{2\pi m k_B T}} \quad \text{for Sr, } m = 87.6 \text{ amu} \\ \text{and } T \approx 1000 \text{ K}$$

Above is maximum evaporation rate. For free evaporation (as in MBE where wide-mouth (Langmuir) sources are used)

$$\Phi = \frac{\alpha P}{\sqrt{2\pi m k_B T}} \quad \alpha \approx 0.1 \\ \text{(coefficient of evaporation)}$$

Vapor pressure P_i needs to be larger by ratio of surface area of substrate to surface area of crucible

$$P_i = \frac{\Phi \sqrt{2\pi m k_B T}}{\alpha} (\text{area ratio}) \approx 10^{-4} - 10^{-3} \text{ Torr}$$

Crucible for Pb Source

Temperature, Degrees Centigrade (°C)

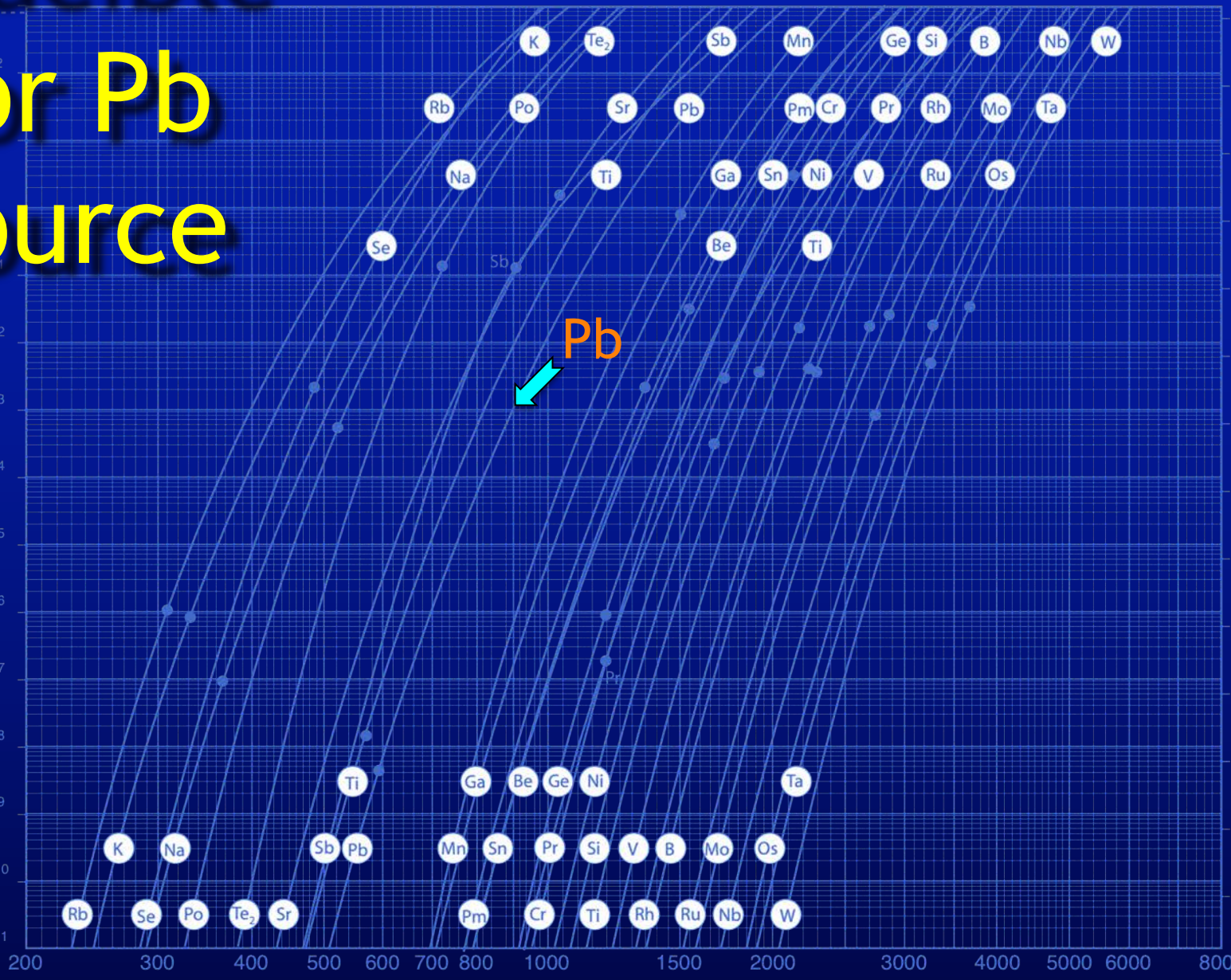
150 200 300 400 500 600 800 1000 1500 2000 3000 4000 5000 6000 7000

BOILING POINT

VAPOR PRESSURE IN TORR (mm Hg)

VAPOR PRESSURE IN ATMOSPHERES

VAPOR PRESSURE IN PASCALS (N/m²)



Pb

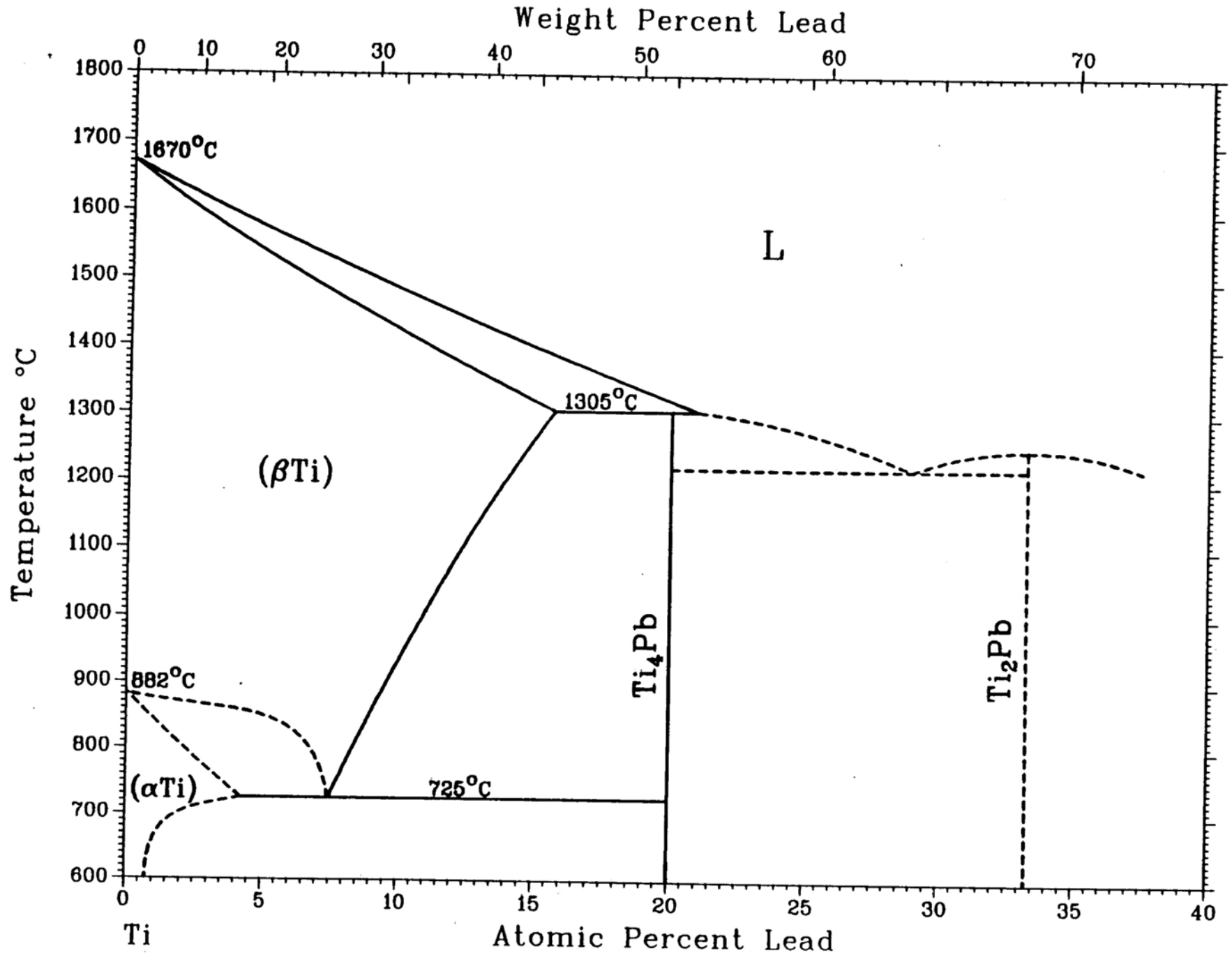
● MELTING POINT
- - - ESTIMATED





Ti-Pb Phase Diagram

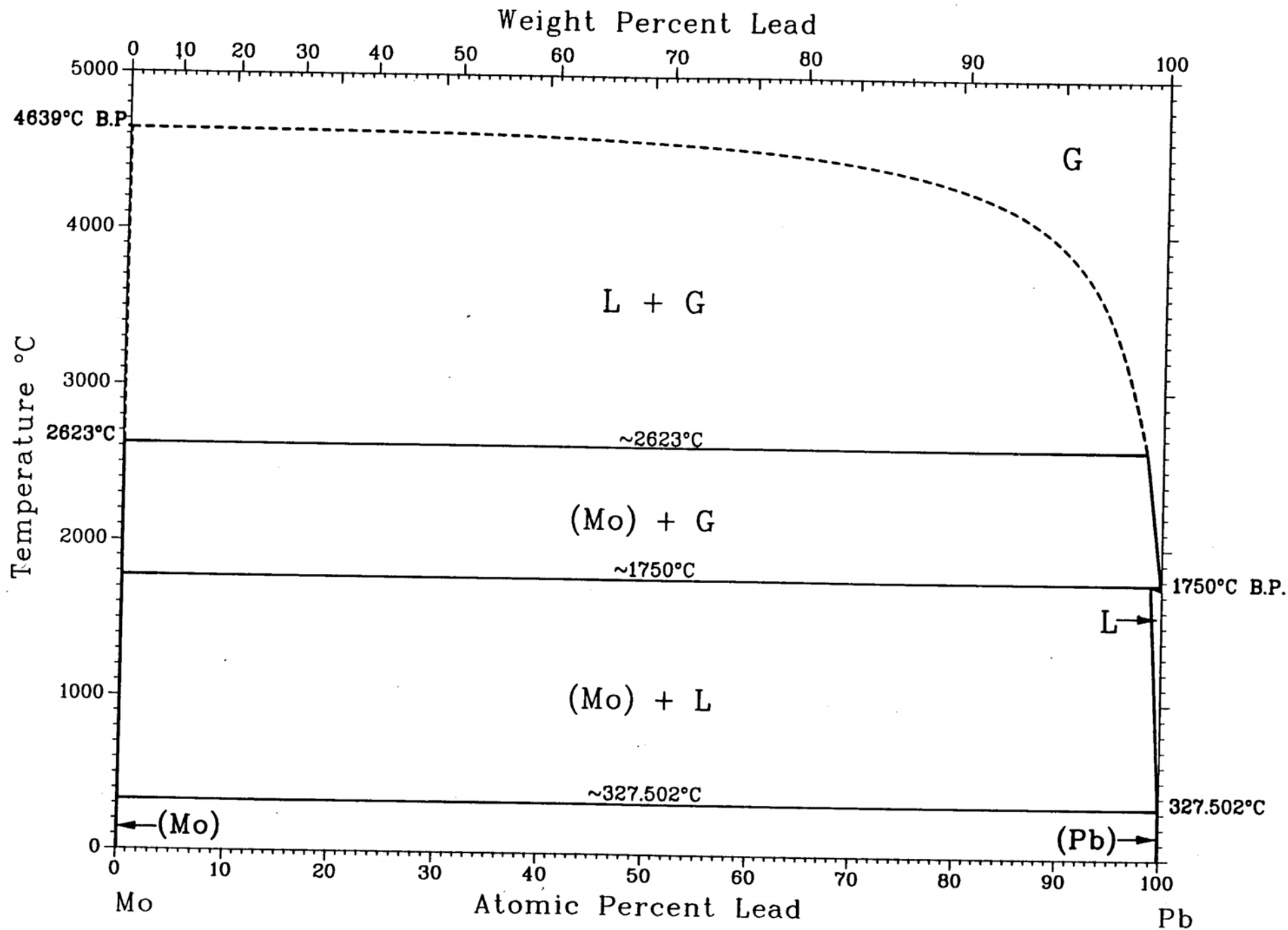
Binary Alloy Phase Diagrams,
edited by T.B. Massalski (ASM International, 1990).





Mo-Pb Phase Diagram

Binary Alloy Phase Diagrams,
edited by T.B. Massalski (ASM International, 1990).



Pb-W (Lead-Tungsten)

S.V. Nagender Naidu and P. Rama Rao



No phase diagram is available for the Pb-W system. The solubility of W in liquid Pb is less than 0.1 at.% W. No intermediate phases exist in the system.

[19Ino] claimed to have determined the solidification temperature of alloys containing up to 30 at.% W at 1300 °C; however, no further details are available in this regard. The findings of [19Ino] are not accepted here because there is no confirming evidence in any of the later experimental investiga-

Pb-W Crystal Structure Data

Phase	Composition, at.% W	Pearson symbol	Space group	Struktur- bericht designation	Prototype
(Pb)	~0	<i>cF4</i>	<i>Fm$\bar{3}m$</i>	A1	Cu
(W)	~100	<i>cI2</i>	<i>Im$\bar{3}m$</i>	A2	W


tions as to the alloy formation.

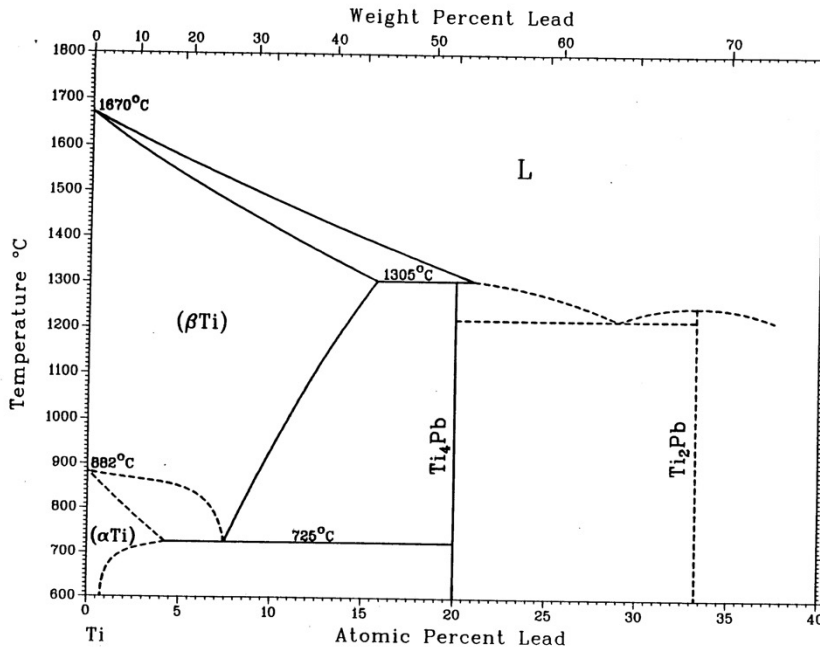
19Ino: S. Inouye, *Mem. Coll. Sci. Kyoto Univ.*, 4, 43-46 (1919) in German.

To be published in *Phase Diagrams of Bi-*

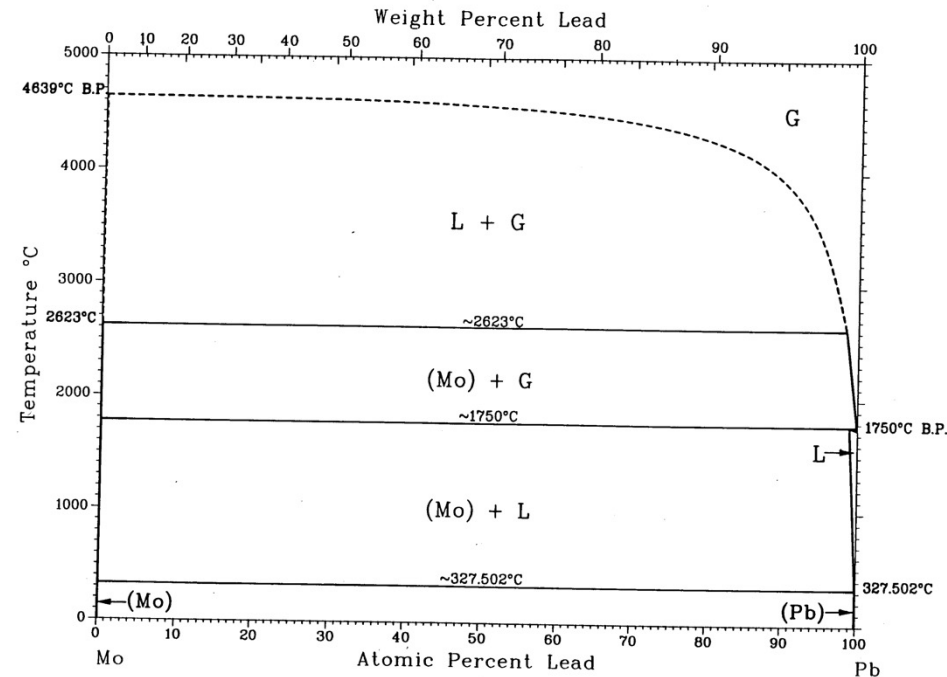
nary Tungsten Alloys, 1991. Complete evaluation contains 1 table and 11 references.

What Crucible to use for Pb?

 Ti-Pb Phase Diagram



 Mo-Pb Phase Diagram



Pb-W (Lead-Tungsten)

S.V. Nagender Naidu and P. Rama Rao

Ti, Mo,
or W?



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Pb-W Crystal Structure Data

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(W).....	~100	cI2	Im $\bar{3}m$	A2	W

tions as to the alloy formation.

19Ino: S. Inouye, *Mem. Coll. Sci. Kyoto Univ.*, 4, 43-46 (1919) in German.

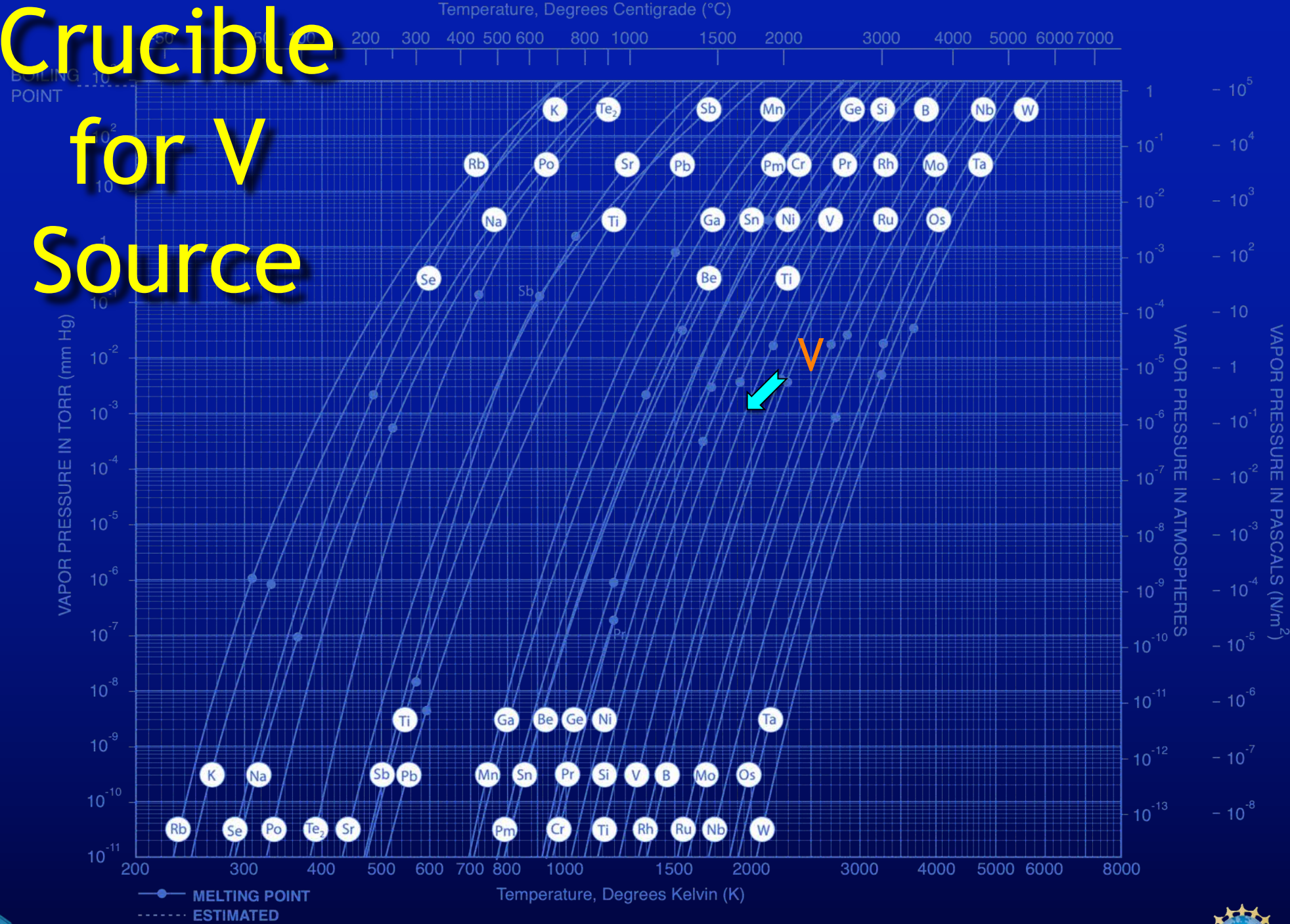
To be published in *Phase Diagrams of Bi-*

nary Tungsten Alloys, 1991. Complete evaluation contains 1 table and 11 references.

Material	Symbol	MP (° C)	S/D	g/cm ³	Temp. (° C) for Given Vap. Press. (Torr)			Evaporation Techniques					Sputter	Comments
					10 ⁻⁶	10 ⁻⁶	10 ⁻⁴	E-Beam	Boat	Coil	Basket	Crucible		
Kanthal	FeCrAl	—	—	7.1	—	—	—	—	W	W	W	—	DC, RF	—
Lanthanum	La	921	—	6.15	990	1,212	1,388	Ex	W, Ta	—	—	Al ₂ O ₃	RF	Films will burn in air if scraped
Lanthanum Boride	LaB ₆	2,210	D	2.61	—	—	—	G	—	—	—	—	RF	—
Lanthanum Bromide	LaBr ₃	783	—	5.06	—	—	—	—	—	—	Ta	—	RF	n=1.94. Hygroscopic
Lanthanum Fluoride	LaF ₃	1,490	S	~6.0	—	—	900	G	Ta, Mo	—	Ta	—	RF	No decomposition. n ~1.6
Lanthanum Oxide	La ₂ O ₃	2,307	—	6.51	—	—	1,400	G	W, Ta	—	—	—	RF	Loses oxygen. n~1.73
Lead	Pb	328	—	11.34	342	427	497	Ex	W, Mo	W	W, Ta	Al ₂ O ₃ , Q	DC,	RF Toxic
Lead Bromide	PbBr ₂	373	—	6.66	—	—	~300	—	—	—	—	—	—	—
Lead Chloride	PbCl ₂	501	—	5.85	—	—	~325	—	Pt	—	—	Al ₂ O ₃	RF	Little decomposition
Lead Fluoride	PbF ₂	855	S	8.24	—	—	~400	—	W, Pt, Mo	—	—	BeO	RF	n = 1.75
Lead Iodide	PbI ₂	402	—	6.16	—	—	~500	—	Pt	—	—	Q	—	—
Lead Oxide	PbO	886	—	9.53	—	—	~550	—	Pt	—	—	Q, Al ₂ O ₃	RF-R	No decomposition. n ~2.6
Lead Selenide	PbSe	1,065	S	8.10	—	—	~500	—	W, Mo	—	W	Gr, Al ₂ O ₃	RF	—
Lead Stannate	PbSnO ₃	1,115	—	8.1	670	780	905	P	Pt	—	Pt	Al ₂ O ₃	RF	Disproportionates
Lead Sulfide	PbS	1,114	S	7.5	—	—	500	—	W	—	W, Mo	Q, Al ₂ O ₃	RF	Little decomposition. n = 3.92
Lead Telluride	PbTe	917	—	8.16	780	910	1,050	—	Mo, Pt, Ta	—	—	Al ₂ O ₃ , Gr	RF	Vapors toxic. Deposits aretellurium rich. Sputtering preferred or co-evaporate from two sources
Lead Titanate	PbTiO ₃	—	—	7.52	—	—	—	—	Ta	—	—	—	RF	—
Lithium	Li	181	—	0.53	227	307	407	G	Ta, SS	—	—	Al ₂ O ₃ , BeO	—	Metal reacts quickly in air
Lithium Bromide	LiBr	550	—	3.46	—	—	~500	—	Ni	—	—	—	RF	n = 1.78
Lithium Chloride	LiCl	605	—	2.07	—	—	400	—	Ni	—	—	—	RF	Preheat gently to outgas. n = 1.66
Lithium Fluoride	LiF	845	—	2.64	875	1,020	1,180	G	Ni, Ta, Mo, W	—	—	Al ₂ O ₃	RF	Rate control important for optical films. Preheat gently to outgas. n = 1.39
Lithium Iodide	LiI	449	—	4.08	—	—	400	—	Mo, W	—	—	—	RF	n = 1.96
Lithium Oxide	Li ₂ O	>1,700	—	2.01	—	—	850	—	Pt, Ir	—	—	—	RF	n = 1.64
Lutetium	Lu	1,663	—	9.84	—	—	1,300	Ex	Ta	—	—	Al ₂ O ₃	RF, DC	—
Lutetium Oxide	Lu ₂ O ₃	—	—	9.42	—	—	1,400	—	Ir	—	—	—	RF	Decomposes

Key of Symbols: * influenced by composition; ** Cr-plated rod or strip; ***all metals alumina coated; **C** = carbon; **Gr** = graphite; **Q** = quartz; **Incl** = Inconel; **VC** = vitreous carbon; **SS** = stainless steel; **Ex** = excellent; **G** = good; **F** = fair; **P** = poor; **S** = sublimes; **D** = decomposes; **RF** = RF sputtering is effective; **RF-R** = reactive RF sputter is effective; **DC** = DC sputtering is effective; **DC-R** = reactive DC sputtering is effective

Crucible for V Source

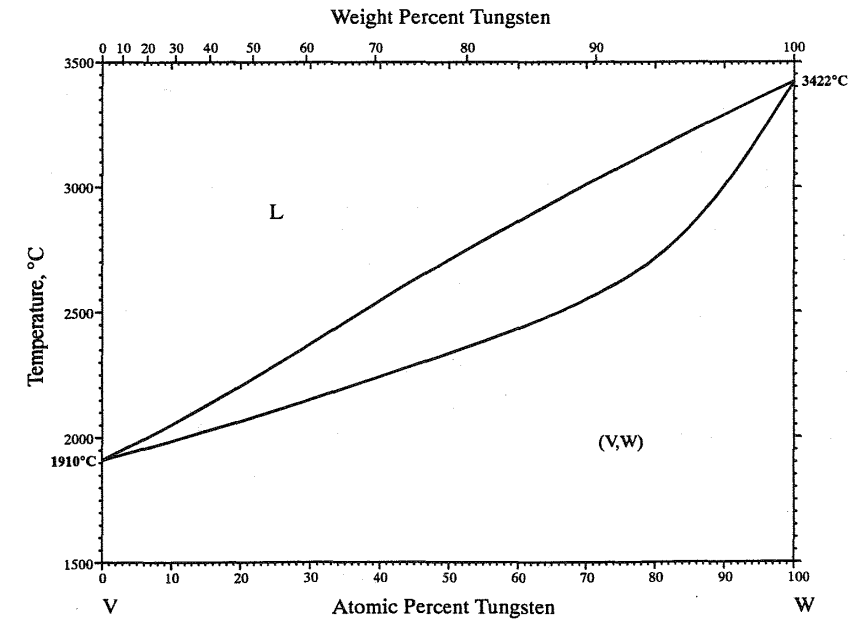
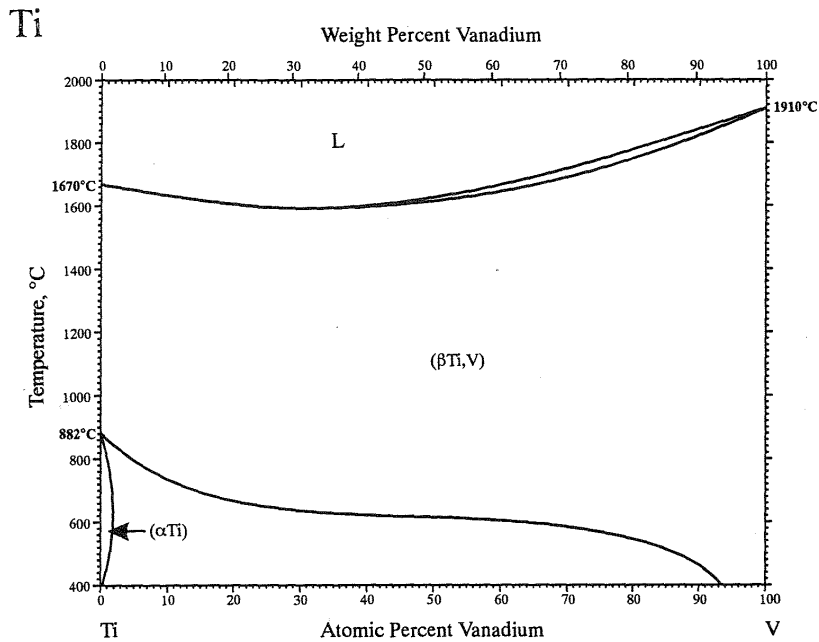
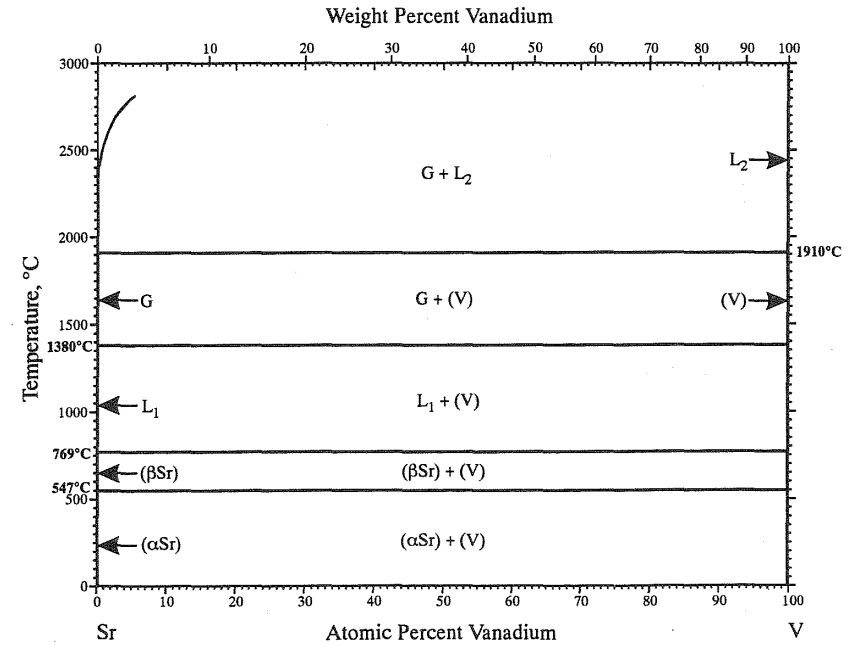
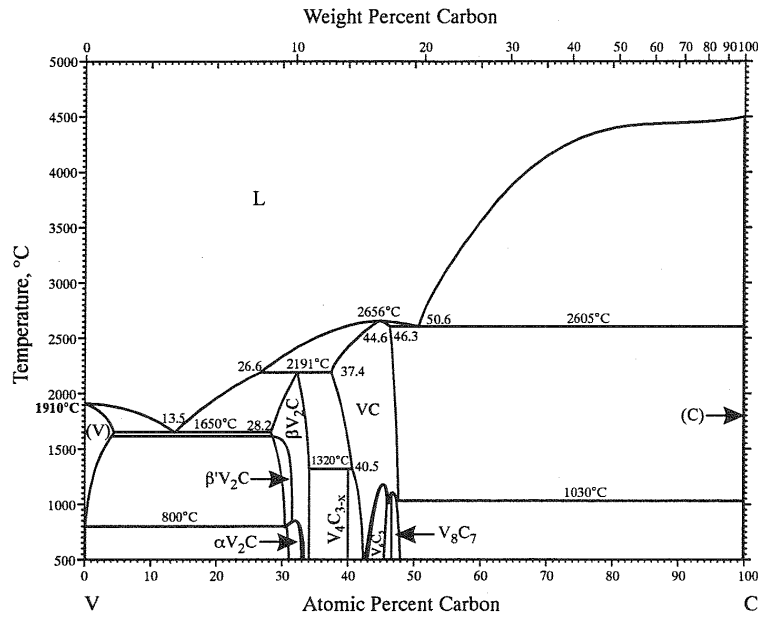


Material	Symbol	MP (° C)	S/D	g/cm ³	Temp. (° C) for Given			Evaporation Techniques					Sputter	Comments	
					Vap. Press. (Torr)			E-Beam	Boat	Thermal Sources					Crucible
					10 ⁻⁵	10 ⁻⁶	10 ⁻⁴			Coil	Basket				
Thulium	Tm	1,545	S	9.32	461	554	680	G	Ta	—	—	Al ₂ O ₃	DC	—	
Thulium Oxide	Tm ₂ O ₃	—	—	8.90	—	—	1,500	—	Ir	—	—	—	RF	Decomposes	
Tin	Sn	232	—	7.28	682	807	997	Ex	Mo	W	W	Al ₂ O ₃	DC, RF	Wets molybdenum Use tantalum liner in E-beam guns	
Tin Oxide	SnO ₂	1,630	S	6.95	—	—	~1,000	Ex	W	W	W	Q, Al ₂ O ₃	RF, RF-R	Films from tungsten are oxygen deficient, oxidize in air. n = 2.0	
Tin Selenide	SnSe	861	—	6.18	—	—	~400	G	—	—	—	Q	RF	—	
Tin Sulfide	SnS	882	—	5.22	—	—	~450	—	—	—	—	Q	RF	—	
Tin Telluride	SnTe	780	D	6.48	—	—	~450	—	—	—	—	Q	RF	—	
Titanium	Ti	1,660	—	4.5	1,067	1,235	1,453	Ex	W	—	—	TiC	DC, RF	Alloys with refractory metals; evolves gas on first heating	
Titanium Boride	TiB ₂	2,900	—	4.50	—	—	—	P	—	—	—	—	RF, DC	—	
Titanium Carbide	TiC	3,140	—	4.93	—	—	~2,300	—	—	—	—	—	RF, DC	—	
Titanium Nitride	TiN	2,930	—	5.22	—	—	—	G	Mo	—	—	—	RF, RF-R, DC	Sputtering preferred. Decomposes with thermal evaporation	
Titanium (II) Oxide	TiO	1,750	—	4.93	—	—	~1,500	G	W, Mo	—	—	VC	RF	Preheat gently to outgas. n = 2.2	
Titanium (III) Oxide	Ti ₂ O ₃	2,130	D	4.6	—	—	—	G	W	—	—	—	RF	Decomposes	
Titanium (IV) Oxide	TiO ₂	1,830	—	4.26	—	—	~1,300	F	W, Mo	—	W	—	RF, RF-R	Suboxide, must be reoxidized to rutile. Tantalum reduces TiO ₂ to TiO and titanium. n = 2.616, 2.903	
Tungsten	W	3,410	—	19.35	2,117	2,407	2,757	G	—	—	—	—	RF, DC	Forms volatile oxides. Films hard and adherent	
Tungsten Boride	WB ₂	~2,900	—	10.77	—	—	—	P	—	—	—	—	RF	—	
Tungsten Carbide	W ₂ C	2,860	—	17.15	1,480	1,720	2,120	Ex	C	—	—	—	RF, DC	—	
Tungsten Disulfide	WS ₂	1,250	D	7.5	—	—	—	—	—	—	—	—	RF	—	
Tungsten Oxide	WO ₃	1,473	S	7.16	—	—	980	G	W, Pt	—	—	—	RF-R	Preheat gently to outgas. Tungsten reduces oxide slightly. n = 1.68	
Tungsten Selenide	WSe ₂	—	—	9.0	—	—	—	—	—	—	—	—	RF	—	
Tungsten Silicide	WSi ₂	>900	—	9.4	—	—	—	—	—	—	—	—	RF, DC	—	
Tungsten Telluride	WTe ₃	—	—	9.49	—	—	—	—	—	—	—	Q	RF	—	
Uranium	U	1,132	—	19.05	1,132	1,327	1,582	G	Mo, W	W	W	—	—	Films oxidize	
Uranium Carbide	UC ₂	2,350	—	11.28	—	—	2,100	—	—	—	—	C	RF	Decomposes	
Uranium Fluoride	UF ₄	960	—	6.70	—	—	300	—	Ni	—	—	—	RF	—	
Uranium (III) Oxide	U ₂ O ₃	1,300	D	8.30	—	—	—	—	W	—	W	—	RF-R	Disproportionates at 1,300° C to UO ₂	
Uranium (IV) Oxide	UO ₂	2,878	—	10.96	—	—	—	—	W	—	W	—	RF	Tantalum causes decomposition	
Uranium Phosphide	UP ₂	—	—	8.57	—	—	1,200	—	Ta	—	—	—	RF	Decomposes	
Uranium (II) Sulfide	US	>2,000	—	10.87	—	—	—	—	—	—	—	—	—	—	
Uranium (IV) Sulfide	US ₂	>1,100	—	7.96	—	—	—	—	W	—	—	—	RF	Slight decomposition	
Vanadium	V	1,890	—	5.96	1,162	1,332	1,547	Ex	W, Mo	—	—	—	DC, RF	Wets molybdenum. E-beam-evaporated films preferred. n = 3.03	
Vanadium Boride	VB ₂	2,400	—	5.10	—	—	—	—	—	—	—	—	RF, DC	—	
Vanadium Carbide	VC	2,810	—	5.77	—	—	~1,800	—	—	—	—	—	RF, DC	—	
Vanadium Nitride	VN	2,320	—	6.13	—	—	—	—	—	—	—	—	RF, RF-R, DC	—	
Vanadium (IV) Oxide	VO ₂	1,967	S	4.34	—	—	~575	—	—	—	—	—	RF, RF-R	Sputtering preferred.	
Vanadium (V) Oxide	V ₂ O ₅	690	D	3.36	—	—	~500	—	—	—	—	Q	RF	n = 1.46, 1.52, 1.76	
Vanadium Silicide	VSi ₂	1,700	—	4.42	—	—	—	—	—	—	—	—	RF	—	
Ytterbium	Yb	819	S	6.96	520	590	690	G	Ta	—	—	—	DC, RF	—	
Ytterbium Fluoride	YbF ₃	1,157	—	—	—	—	~800	—	Mo	—	—	—	RF	—	
Ytterbium Oxide	Yb ₂ O ₃	2,346	S	9.17	—	—	~1,500	—	Ir	—	—	—	RF, RF-R	Loses oxygen	

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What Crucible to use for V?

Desk Handbook:
Phase Diagrams for Binary Alloys,
edited by H. Okamoto (ASM
International, 2000).



C,
Sr,
Ti,
W?

Reactions with Boron Nitride (PBN)

Expected Reactions as calculated from free energies

H 1																	He 2
Li 3	Be 4											B 5	C 6	N 7	O 8	F 9	Ne 10
Na 11	Mg 12											Al 13	Si 14	P 15	S 16	Cl 17	Ar 18
K 19	Ca 20	Sc 21	Ti 22	V 23	Cr 24	Mn 25	Fe 26	Co 27	Ni 28	Cu 29	Zn 30	Ga 31	Ge 32	As 33	Se 34	Br 35	Kr 36
Rb 37	Sr 38	Y 39	Zr 40	Nb 41	Mo 42	Tc 43	Ru 44	Rh 45	Pd 46	Ag 47	Cd 48	In 49	Sn 50	Sb 51	Te 52	I 53	Xe 54
Cs 55	Ba 56	La 57	Hf 72	Ta 73	W 74	Re 75	Os 76	Ir 77	Pt 78	Au 79	Hg 80	Tl 81	Pb 82	Bi 83	Po 84	At 85	Rn 86
Fr 87	Ra 88	Ac 89	103														

Ce 58	Pr 59	Nd 60	Pm 61	Sm 62	Eu 63	Gd 64	Tb 65	Dy 66	Ho 67	Er 68	Tm 69	Yb 70	Lu 71
Th 90	Pa 91	U 92	Np 93	Pu 94	Am 95	Cm 96	Bk 97	Cf 98	Es 99	Fm 100	Md 101	Lw 103	

Reactions with Carbon (PG)

Expected Reactions as calculated from free energies

H 1																	He 2
Li 3	Be 4											B 5	C 6	N 7	O 8	F 9	Ne 10
Na 11	Mg 12											Al 13	Si 14	P 15	S 16	Cl 17	Ar 18
K 19	Ca 20	Sc 21	Ti 22	V 23	Cr 24	Mn 25	Fe 26	Co 27	Ni 28	Cu 29	Zn 30	Ga 31	Ge 32	As 33	Se 34	Br 35	Kr 36
Rb 37	Sr 38	Y 39	Zr 40	Nb 41	Mo 42	Tc 43	Ru 44	Rh 45	Pd 46	Ag 47	Cd 48	In 49	Sn 50	Sb 51	Te 52	I 53	Xe 54
Cs 55	Ba 56	La 57	Hf 72	Ta 73	W 74	Re 75	Os 76	Ir 77	Pt 78	Au 79	Hg 80	Tl 81	Pb 82	Bi 83	Po 84	At 85	Rn 86
Fr 87	Ra 88	Ac 89	103														

Ce 58	Pr 59	Nd 60	Pm 61	Sm 62	Eu 63	Gd 64	Tb 65	Dy 66	Ho 67	Er 68	Tm 69	Yb 70	Lu 71
Th 90	Pa 91	U 92	Np 93	Pu 94	Am 95	Cm 96	Bk 97	Cf 98	Es 99	Fm 100	Md 101	Lw 103	

Reactions with NbC & TaC

Expected Reactions as calculated from free energies

H 1																	He 2
Li 3	Be 4											B 5	C 6	N 7	O 8	F 9	Ne 10
Na 11	Mg 12											Al 13	Si 14	P 15	S 16	Cl 17	Ar 18
K 19	Ca 20	Sc 21	Ti 22	V 23	Cr 24	Mn 25	Fe 26	Co 27	Ni 28	Cu 29	Zn 30	Ga 31	Ge 32	As 33	Se 34	Br 35	Kr 36
Rb 37	Sr 38	Y 39	Zr 40	Nb 41	Mo 42	Tc 43	Ru 44	Rh 45	Pd 46	Ag 47	Cd 48	In 49	Sn 50	Sb 51	Te 52	I 53	Xe 54
Cs 55	Ba 56	La 57	Hf 72	Ta 73	W 74	Re 75	Os 76	Ir 77	Pt 78	Au 79	Hg 80	Tl 81	Pb 82	Bi 83	Po 84	At 85	Rn 86
Fr 87	Ra 88	Ac 89	103														

Ce 58	Pr 59	Nd 60	Pm 61	Sm 62	Eu 63	Gd 64	Tb 65	Dy 66	Ho 67	Er 68	Tm 69	Yb 70	Lu 71
Th 90	Pa 91	U 92	Np 93	Pu 94	Am 95	Cm 96	Bk 97	Cf 98	Es 99	Fm 100	Md 101	Lw 103	

Reactions with SiC

Expected Reactions as calculated from free energies

H 1																	He 2
Li 3	Be 4											B 5	C 6	N 7	O 8	F 9	Ne 10
Na 11	Mg 12											Al 13	Si 14	P 15	S 16	Cl 17	Ar 18
K 19	Ca 20	Sc 21	Ti 22	V 23	Cr 24	Mn 25	Fe 26	Co 27	Ni 28	Cu 29	Zn 30	Ga 31	Ge 32	As 33	Se 34	Br 35	Kr 36
Rb 37	Sr 38	Y 39	Zr 40	Nb 41	Mo 42	Tc 43	Ru 44	Rh 45	Pd 46	Ag 47	Cd 48	In 49	Sn 50	Sb 51	Te 52	I 53	Xe 54
Cs 55	Ba 56	La 57	Hf 72	Ta 73	W 74	Re 75	Os 76	Ir 77	Pt 78	Au 79	Hg 80	Tl 81	Pb 82	Bi 83	Po 84	At 85	Rn 86
Fr 87	Ra 88	Ac 89	103														

Ce 58	Pr 59	Nd 60	Pm 61	Sm 62	Eu 63	Gd 64	Tb 65	Dy 66	Ho 67	Er 68	Tm 69	Yb 70	Lu 71
Th 90	Pa 91	U 92	Np 93	Pu 94	Am 95	Cm 96	Bk 97	Cf 98	Es 99	Fm 100	Md 101	Lw 103	